



M29W160ET M29W160EB

16 Mbit (2Mb x8 or 1Mb x16, Boot Block)
3V Supply Flash Memory

FEATURES SUMMARY

- SUPPLY VOLTAGE
 - $V_{CC} = 2.7V$ to $3.6V$ for Program, Erase and Read
- ACCESS TIME: 70, 90ns
- PROGRAMMING TIME
 - $10\mu s$ per Byte/Word typical
- 35 MEMORY BLOCKS
 - 1 Boot Block (Top or Bottom Location)
 - 2 Parameter and 32 Main Blocks
- PROGRAM/ERASE CONTROLLER
 - Embedded Byte/Word Program algorithms
- ERASE SUSPEND and RESUME MODES
 - Read and Program another Block during Erase Suspend
- UNLOCK BYPASS PROGRAM COMMAND
 - Faster Production/Batch Programming
- TEMPORARY BLOCK UNPROTECTION MODE
- COMMON FLASH INTERFACE
 - 64 bit Security Code
- LOW POWER CONSUMPTION
 - Standby and Automatic Standby
- 100,000 PROGRAM/ERASE CYCLES per BLOCK
- ELECTRONIC SIGNATURE
 - Manufacturer Code: 0020h
 - Top Device Code M29W160ET: 22C4h
 - Bottom Device Code M29W160EB: 2249h

Figure 1. Packages



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SUMMARY DESCRIPTION

The M29W160E is a 16 Mbit (2Mb x8 or 1Mb x16) non-volatile memory that can be read, erased and reprogrammed. These operations can be performed using a single low voltage (2.7 to 3.6V) supply. On power-up the memory defaults to its Read mode where it can be read in the same way as a ROM or EPROM.

The memory is divided into blocks that can be erased independently so it is possible to preserve valid data while old data is erased. Each block can be protected independently to prevent accidental Program or Erase commands from modifying the memory. Program and Erase commands are written to the Command Interface of the memory. An on-chip Program/Erase Controller simplifies the process of programming or erasing the memory by taking care of all of the special operations that are required to update the memory contents.

The end of a program or erase operation can be detected and any error conditions identified. The

command set required to control the memory is consistent with JEDEC standards.

The blocks in the memory are asymmetrically arranged, see Figures 5 and 6, Block Addresses. The first or last 64 KBytes have been divided into four additional blocks. The 16 KByte Boot Block can be used for small initialization code to start the microprocessor, the two 8 KByte Parameter Blocks can be used for parameter storage and the remaining 32K is a small Main Block where the application may be stored.

Chip Enable, Output Enable and Write Enable signals control the bus operation of the memory. They allow simple connection to most microprocessors, often without additional logic.

The memory is offered TSOP48 (12 x 20mm) and TFBGA48 (0.8mm pitch) packages. The memory is supplied with all the bits erased (set to '1').

Figure 2. Logic Diagram

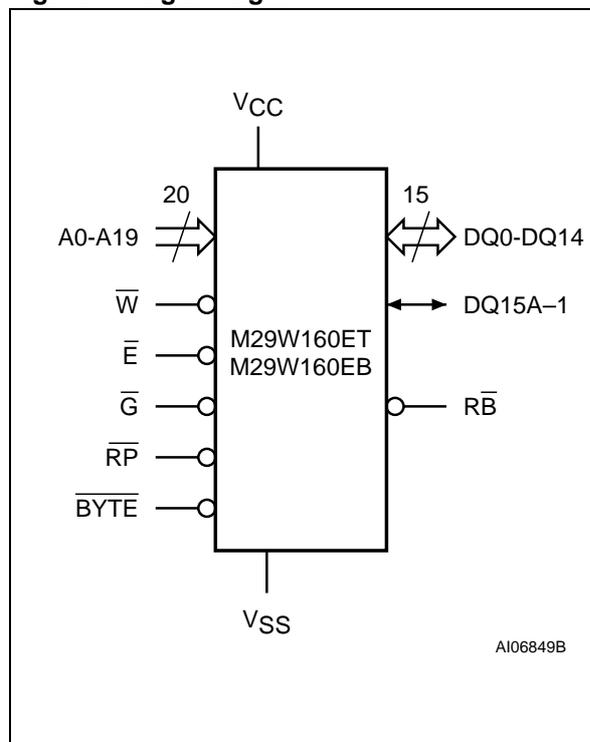


Table 1. Signal Names

| | |
|-----------------|------------------------------------|
| A0-A19 | Address Inputs |
| DQ0-DQ7 | Data Inputs/Outputs |
| DQ8-DQ14 | Data Inputs/Outputs |
| DQ15A-1 | Data Input/Output or Address Input |
| \bar{E} | Chip Enable |
| \bar{G} | Output Enable |
| \bar{W} | Write Enable |
| \bar{RP} | Reset/Block Temporary Unprotect |
| \bar{RB} | Ready/Busy Output |
| \bar{BYTE} | Byte/Word Organization Select |
| V _{CC} | Supply Voltage |
| V _{SS} | Ground |
| NC | Not Connected Internally |

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Figure 3. TSOP Connections

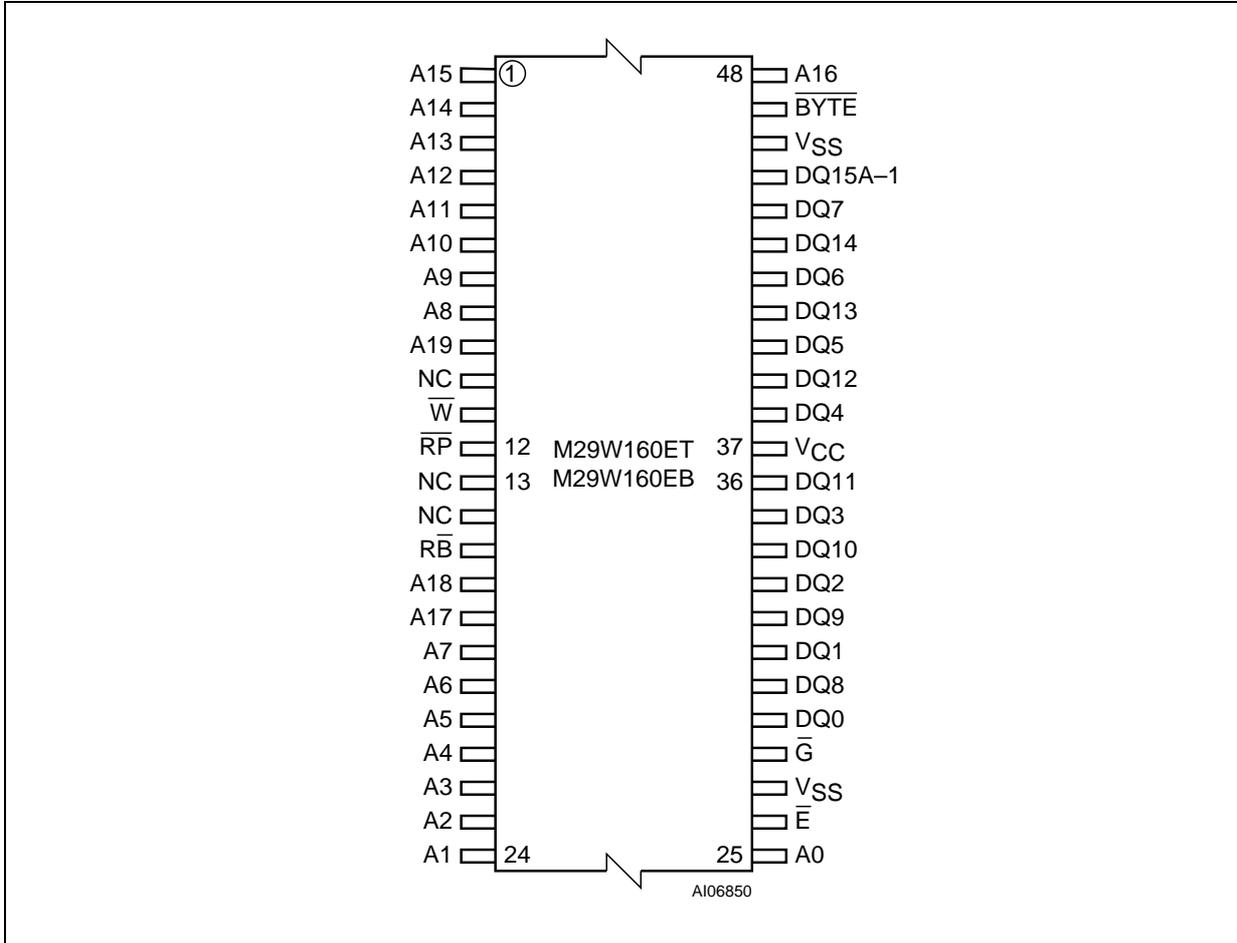
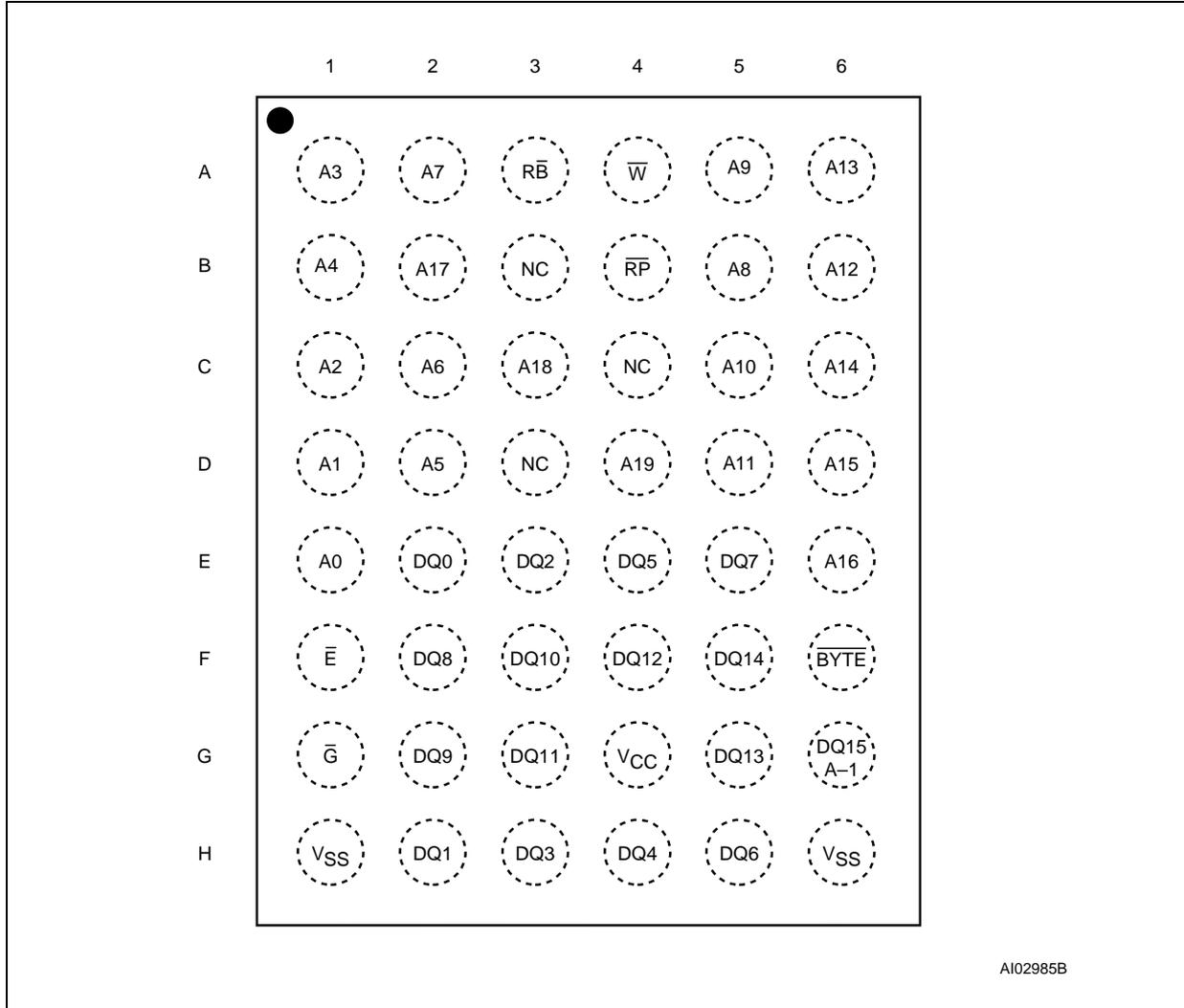
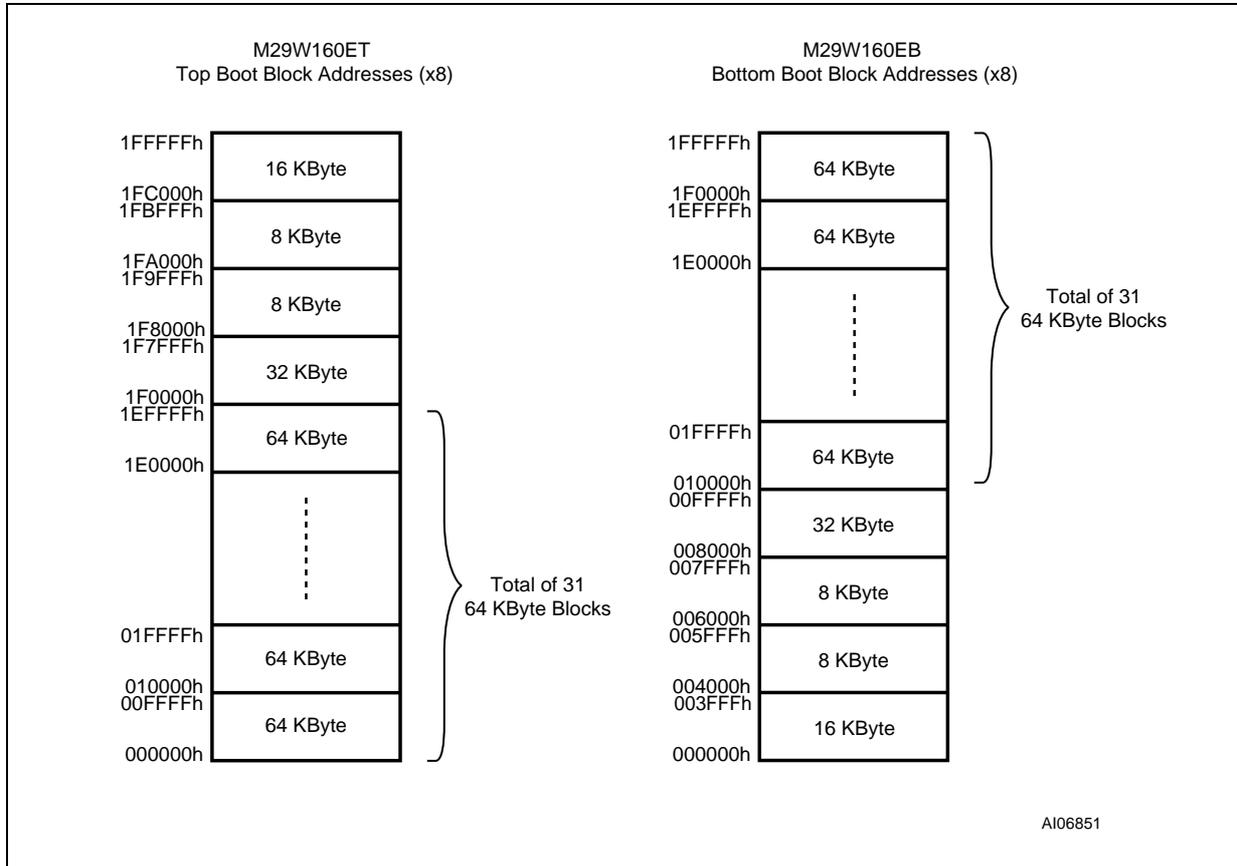


Figure 4. TFBGA Connections (Top view through package)



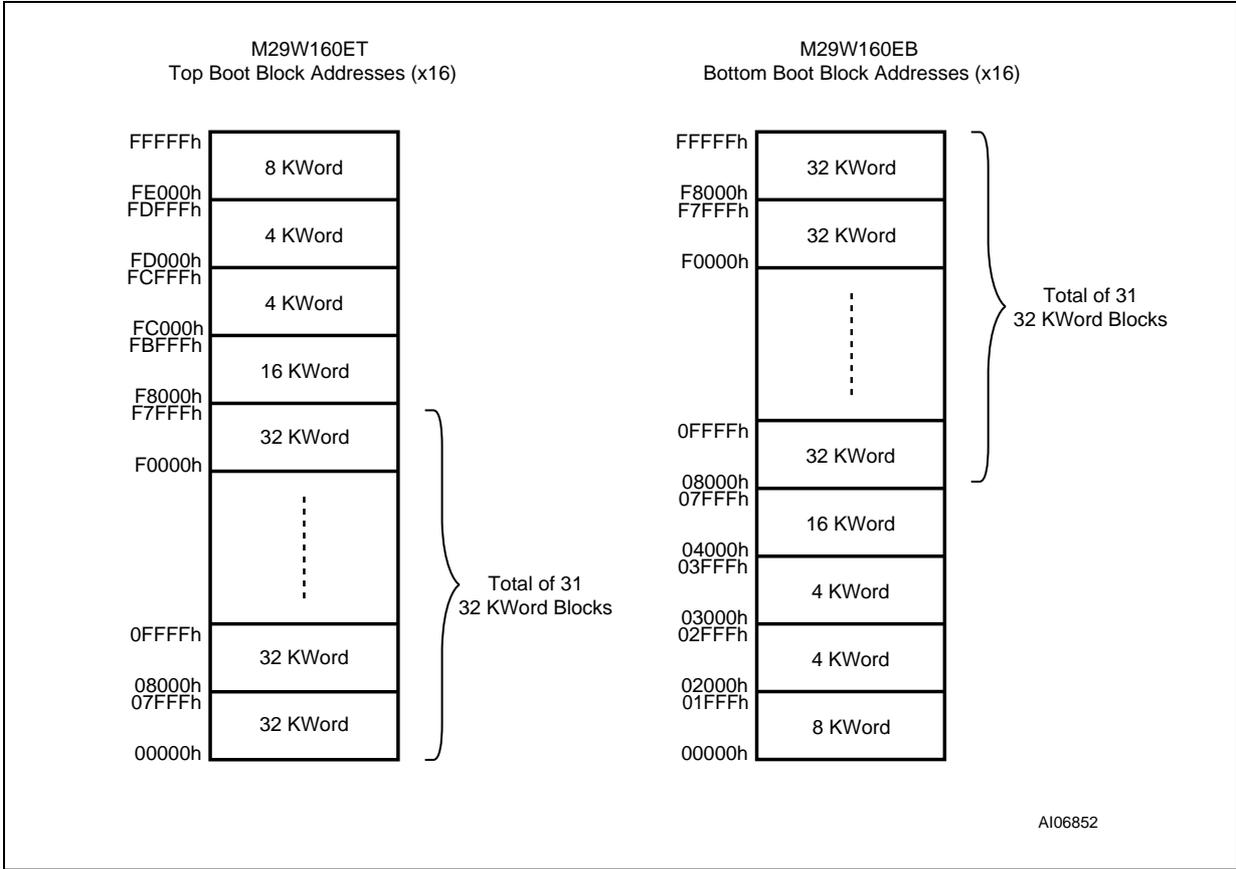
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Figure 5. Block Addresses (x8)



Note: Also see Appendix A, Tables 19 and 20 for a full listing of the Block Addresses.

Figure 6. Block Addresses (x16)



Note: Also see Appendix A, Tables 19 and 20 for a full listing of the Block Addresses.

SIGNAL DESCRIPTIONS

See Figure 2, Logic Diagram, and Table 1, Signal Names, for a brief overview of the signals connected to this device.

Address Inputs (A0-A19). The Address Inputs select the cells in the memory array to access during Bus Read operations. During Bus Write operations they control the commands sent to the Command Interface of the Program/Erase Controller.

Data Inputs/Outputs (DQ0-DQ7). The Data Inputs/Outputs output the data stored at the selected address during a Bus Read operation. During Bus Write operations they represent the commands sent to the Command Interface of the Program/Erase Controller.

Data Inputs/Outputs (DQ8-DQ14). The Data Inputs/Outputs output the data stored at the selected address during a Bus Read operation when $\overline{\text{BYTE}}$ is High, V_{IH} . When $\overline{\text{BYTE}}$ is Low, V_{IL} , these pins are not used and are high impedance. During Bus Write operations the Command Register does not use these bits. When reading the Status Register these bits should be ignored.

Data Input/Output or Address Input (DQ15A-1).

When $\overline{\text{BYTE}}$ is High, V_{IH} , this pin behaves as a Data Input/Output pin (as DQ8-DQ14). When $\overline{\text{BYTE}}$ is Low, V_{IL} , this pin behaves as an address pin; DQ15A-1 Low will select the LSB of the Word on the other addresses, DQ15A-1 High will select the MSB. Throughout the text consider references to the Data Input/Output to include this pin when $\overline{\text{BYTE}}$ is High and references to the Address Inputs to include this pin when $\overline{\text{BYTE}}$ is Low except when stated explicitly otherwise.

Chip Enable ($\overline{\text{E}}$). The Chip Enable, $\overline{\text{E}}$, activates the memory, allowing Bus Read and Bus Write operations to be performed. When Chip Enable is High, V_{IH} , all other pins are ignored.

Output Enable ($\overline{\text{G}}$). The Output Enable, $\overline{\text{G}}$, controls the Bus Read operation of the memory.

Write Enable ($\overline{\text{W}}$). The Write Enable, $\overline{\text{W}}$, controls the Bus Write operation of the memory's Command Interface.

Reset/Block Temporary Unprotect ($\overline{\text{RP}}$). The Reset/Block Temporary Unprotect pin can be used to apply a Hardware Reset to the memory or to temporarily unprotect all Blocks that have been protected.

A Hardware Reset is achieved by holding Reset/Block Temporary Unprotect Low, V_{IL} , for at least t_{PLPX} . After Reset/Block Temporary Unprotect goes High, V_{IH} , the memory will be ready for Bus

Read and Bus Write operations after t_{PHEL} or t_{RHEL} , whichever occurs last. See the Ready/Busy Output section, Table 15 and Figure 14, Reset/Temporary Unprotect AC Characteristics for more details.

Holding $\overline{\text{RP}}$ at V_{ID} will temporarily unprotect the protected Blocks in the memory. Program and Erase operations on all blocks will be possible. The transition from V_{IH} to V_{ID} must be slower than t_{PHPHH} .

Ready/Busy Output ($\overline{\text{RB}}$). The Ready/Busy pin is an open-drain output that can be used to identify when the device is performing a Program or Erase operation. During Program or Erase operations Ready/Busy is Low, V_{OL} . Ready/Busy is high-impedance during Read mode, Auto Select mode and Erase Suspend mode.

After a Hardware Reset, Bus Read and Bus Write operations cannot begin until Ready/Busy becomes high-impedance. See Table 15 and Figure 14, Reset/Temporary Unprotect AC Characteristics.

The use of an open-drain output allows the Ready/Busy pins from several memories to be connected to a single pull-up resistor. A Low will then indicate that one, or more, of the memories is busy.

Byte/Word Organization Select ($\overline{\text{BYTE}}$). The Byte/Word Organization Select pin is used to switch between the 8-bit and 16-bit Bus modes of the memory. When Byte/Word Organization Select is Low, V_{IL} , the memory is in 8-bit mode, when it is High, V_{IH} , the memory is in 16-bit mode.

V_{CC} Supply Voltage. The V_{CC} Supply Voltage supplies the power for all operations (Read, Program, Erase etc.).

The Command Interface is disabled when the V_{CC} Supply Voltage is less than the Lockout Voltage, V_{LKO} . This prevents Bus Write operations from accidentally damaging the data during power up, power down and power surges. If the Program/Erase Controller is programming or erasing during this time then the operation aborts and the memory contents being altered will be invalid.

A 0.1 μF capacitor should be connected between the V_{CC} Supply Voltage pin and the V_{SS} Ground pin to decouple the current surges from the power supply. The PCB track widths must be sufficient to carry the currents required during program and erase operations, I_{CC3} .

V_{SS} Ground. The V_{SS} Ground is the reference for all voltage measurements. The two V_{SS} pins of the device must be connected to the system ground.

BUS OPERATIONS

There are five standard bus operations that control the device. These are Bus Read, Bus Write, Output Disable, Standby and Automatic Standby. See Tables 2 and 3, Bus Operations, for a summary. Typically glitches of less than 5ns on Chip Enable or Write Enable are ignored by the memory and do not affect bus operations.

Bus Read. Bus Read operations read from the memory cells, or specific registers in the Command Interface. A valid Bus Read operation involves setting the desired address on the Address Inputs, applying a Low signal, V_{IL} , to Chip Enable and Output Enable and keeping Write Enable High, V_{IH} . The Data Inputs/Outputs will output the value, see Figure 11, Read Mode AC Waveforms, and Table 12, Read AC Characteristics, for details of when the output becomes valid.

Bus Write. Bus Write operations write to the Command Interface. A valid Bus Write operation begins by setting the desired address on the Address Inputs. The Address Inputs are latched by the Command Interface on the falling edge of Chip Enable or Write Enable, whichever occurs last. The Data Inputs/Outputs are latched by the Command Interface on the rising edge of Chip Enable or Write Enable, whichever occurs first. Output Enable must remain High, V_{IH} , during the whole Bus Write operation. See Figures 12 and 13, Write AC Waveforms, and Tables 13 and 14, Write AC Characteristics, for details of the timing requirements.

Output Disable. The Data Inputs/Outputs are in the high impedance state when Output Enable is High, V_{IH} .

Standby. When Chip Enable is High, V_{IH} , the memory enters Standby mode and the Data Inputs/Outputs pins are placed in the high-imped-

ance state. To reduce the Supply Current to the Standby Supply Current, I_{CC2} , Chip Enable should be held within $V_{CC} \pm 0.2V$. For the Standby current level see Table 11, DC Characteristics.

During program or erase operations the memory will continue to use the Program/Erase Supply Current, I_{CC3} , for Program or Erase operations until the operation completes.

Automatic Standby. If CMOS levels ($V_{CC} \pm 0.2V$) are used to drive the bus and the bus is inactive for 150ns or more the memory enters Automatic Standby where the internal Supply Current is reduced to the Standby Supply Current, I_{CC2} . The Data Inputs/Outputs will still output data if a Bus Read operation is in progress.

Special Bus Operations. Additional bus operations can be performed to read the Electronic Signature and also to apply and remove Block Protection. These bus operations are intended for use by programming equipment and are not usually used in applications. They require V_{ID} to be applied to some pins.

Electronic Signature. The memory has two codes, the manufacturer code and the device code, that can be read to identify the memory. These codes can be read by applying the signals listed in Tables 2 and 3, Bus Operations.

Block Protection and Blocks Unprotection.

Each block can be separately protected against accidental Program or Erase. Protected blocks can be unprotected to allow data to be changed.

There are two methods available for protecting and unprotecting the blocks, one for use on programming equipment and the other for in-system use. Block Protect and Blocks Unprotect operations are described in Appendix C.

Table 2. Bus Operations, $\overline{BYTE} = V_{IL}$

| Operation | \overline{E} | \overline{G} | \overline{W} | Address Inputs DQ15A-1, A0-A19 | Data Inputs/Outputs | |
|------------------------|----------------|----------------|----------------|--|---------------------|------------------------------------|
| | | | | | DQ14-DQ8 | DQ7-DQ0 |
| Bus Read | V_{IL} | V_{IL} | V_{IH} | Cell Address | Hi-Z | Data Output |
| Bus Write | V_{IL} | V_{IH} | V_{IL} | Command Address | Hi-Z | Data Input |
| Output Disable | X | V_{IH} | V_{IH} | X | Hi-Z | Hi-Z |
| Standby | V_{IH} | X | X | X | Hi-Z | Hi-Z |
| Read Manufacturer Code | V_{IL} | V_{IL} | V_{IH} | A0 = V_{IL} , A1 = V_{IL} , A9 = V_{ID} , Others V_{IL} or V_{IH} | Hi-Z | 20h |
| Read Device Code | V_{IL} | V_{IL} | V_{IH} | A0 = V_{IH} , A1 = V_{IL} , A9 = V_{ID} , Others V_{IL} or V_{IH} | Hi-Z | C4h (M29W160ET) 49h (M29W160EB) |

Note: X = V_{IL} or V_{IH} .

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Table 3. Bus Operations, $\overline{\text{BYTE}} = V_{IH}$

| Operation | $\overline{\text{E}}$ | $\overline{\text{G}}$ | $\overline{\text{W}}$ | Address Inputs A0-A19 | Data Inputs/Outputs DQ15A-1, DQ14-DQ0 |
|------------------------|-----------------------|-----------------------|-----------------------|--|--|
| Bus Read | V_{IL} | V_{IL} | V_{IH} | Cell Address | Data Output |
| Bus Write | V_{IL} | V_{IH} | V_{IL} | Command Address | Data Input |
| Output Disable | X | V_{IH} | V_{IH} | X | Hi-Z |
| Standby | V_{IH} | X | X | X | Hi-Z |
| Read Manufacturer Code | V_{IL} | V_{IL} | V_{IH} | A0 = V_{IL} , A1 = V_{IL} , A9 = V_{ID} , Others V_{IL} or V_{IH} | 0020h |
| Read Device Code | V_{IL} | V_{IL} | V_{IH} | A0 = V_{IH} , A1 = V_{IL} , A9 = V_{ID} , Others V_{IL} or V_{IH} | 22C4h (M29W160ET) 2249h (M29W160EB) |

Note: X = V_{IL} or V_{IH} .

COMMAND INTERFACE

All Bus Write operations to the memory are interpreted by the Command Interface. Commands consist of one or more sequential Bus Write operations. Failure to observe a valid sequence of Bus Write operations will result in the memory returning to Read mode. The long command sequences are imposed to maximize data security.

The address used for the commands changes depending on whether the memory is in 16-bit or 8-bit mode. See either Table 4, or 5, depending on the configuration that is being used, for a summary of the commands.

Read/Reset Command. The Read/Reset command returns the memory to its Read mode where it behaves like a ROM or EPROM, unless otherwise stated. It also resets the errors in the Status Register. Either one or three Bus Write operations can be used to issue the Read/Reset command.

The Read/Reset Command can be issued, between Bus Write cycles before the start of a program or erase operation, to return the device to read mode. Once the program or erase operation has started the Read/Reset command is no longer accepted. The Read/Reset command will not abort an Erase operation when issued while in Erase Suspend.

Auto Select Command. The Auto Select command is used to read the Manufacturer Code, the Device Code and the Block Protection Status. Three consecutive Bus Write operations are required to issue the Auto Select command. Once the Auto Select command is issued the memory remains in Auto Select mode until a Read/Reset command is issued. Read CFI Query and Read/Reset commands are accepted in Auto Select mode, all other commands are ignored.

From the Auto Select mode the Manufacturer Code can be read using a Bus Read operation with A0 = V_{IL} and A1 = V_{IL} . The other address bits may be set to either V_{IL} or V_{IH} . The Manufacturer Code for STMicroelectronics is 0020h.

The Device Code can be read using a Bus Read operation with A0 = V_{IH} and A1 = V_{IL} . The other address bits may be set to either V_{IL} or V_{IH} . The Device Code for the M29W160ET is 22C4h and for the M29W160EB is 2249h.

The Block Protection Status of each block can be read using a Bus Read operation with A0 = V_{IL} , A1 = V_{IH} , and A12-A19 specifying the address of the block. The other address bits may be set to either V_{IL} or V_{IH} . If the addressed block is protected then 01h is output on Data Inputs/Outputs DQ0-DQ7, otherwise 00h is output.

Program Command. The Program command can be used to program a value to one address in the memory array at a time. The command requires four Bus Write operations, the final write operation latches the address and data, and starts the Program/Erase Controller.

If the address falls in a protected block then the Program command is ignored, the data remains unchanged. The Status Register is never read and no error condition is given.

During the program operation the memory will ignore all commands. It is not possible to issue any command to abort or pause the operation. Typical program times are given in Table 6. Bus Read operations during the program operation will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the program operation has completed the memory will return to the Read mode, unless an

error has occurred. When an error occurs the memory will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

Note that the Program command cannot change a bit set at '0' back to '1'. One of the Erase Commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

Unlock Bypass Command. The Unlock Bypass command is used in conjunction with the Unlock Bypass Program command to program the memory. When the access time to the device is long (as with some EPROM programmers) considerable time saving can be made by using these commands. Three Bus Write operations are required to issue the Unlock Bypass command.

Once the Unlock Bypass command has been issued the memory will only accept the Unlock Bypass Program command and the Unlock Bypass Reset command. The memory can be read as if in Read mode.

Unlock Bypass Program Command. The Unlock Bypass Program command can be used to program one address in memory at a time. The command requires two Bus Write operations, the final write operation latches the address and data, and starts the Program/Erase Controller.

The Program operation using the Unlock Bypass Program command behaves identically to the Program operation using the Program command. A protected block cannot be programmed; the operation cannot be aborted and the Status Register is read. Errors must be reset using the Read/Reset command, which leaves the device in Unlock Bypass Mode. See the Program command for details on the behavior.

Unlock Bypass Reset Command. The Unlock Bypass Reset command can be used to return to Read/Reset mode from Unlock Bypass Mode. Two Bus Write operations are required to issue the Unlock Bypass Reset command. Read/Reset command does not exit from Unlock Bypass Mode.

Chip Erase Command. The Chip Erase command can be used to erase the entire chip. Six Bus Write operations are required to issue the Chip Erase Command and start the Program/Erase Controller.

If any blocks are protected then these are ignored and all the other blocks are erased. If all of the blocks are protected the Chip Erase operation appears to start but will terminate within about 100 μ s, leaving the data unchanged. No error condition is given when protected blocks are ignored.

During the erase operation the memory will ignore all commands. It is not possible to issue any command to abort the operation. Typical chip erase

times are given in Table 6. All Bus Read operations during the Chip Erase operation will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the Chip Erase operation has completed the memory will return to the Read Mode, unless an error has occurred. When an error occurs the memory will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read Mode.

The Chip Erase Command sets all of the bits in unprotected blocks of the memory to '1'. All previous data is lost.

Block Erase Command. The Block Erase command can be used to erase a list of one or more blocks. Six Bus Write operations are required to select the first block in the list. Each additional block in the list can be selected by repeating the sixth Bus Write operation using the address of the additional block. The Block Erase operation starts the Program/Erase Controller about 50 μ s after the last Bus Write operation. Once the Program/Erase Controller starts it is not possible to select any more blocks. Each additional block must therefore be selected within 50 μ s of the last block. The 50 μ s timer restarts when an additional block is selected. The Status Register can be read after the sixth Bus Write operation. See the Status Register section for details on how to identify if the Program/Erase Controller has started the Block Erase operation.

If any selected blocks are protected then these are ignored and all the other selected blocks are erased. If all of the selected blocks are protected the Block Erase operation appears to start but will terminate within about 100 μ s, leaving the data unchanged. No error condition is given when protected blocks are ignored.

During the Block Erase operation the memory will ignore all commands except the Erase Suspend and Read/Reset commands. Typical block erase times are given in Table 6. All Bus Read operations during the Block Erase operation will output the Status Register on the Data Inputs/Outputs. See the section on the Status Register for more details.

After the Block Erase operation has completed the memory will return to the Read Mode, unless an error has occurred. When an error occurs the memory will continue to output the Status Register. A Read/Reset command must be issued to reset the error condition and return to Read mode.

The Block Erase Command sets all of the bits in the unprotected selected blocks to '1'. All previous data in the selected blocks is lost.

Erase Suspend Command. The Erase Suspend Command may be used to temporarily suspend a Block Erase operation and return the memory to Read mode. The command requires one Bus Write operation.

The Program/Erase Controller will suspend within the Erase Suspend Latency Time (refer to Table 6 for value) of the Erase Suspend Command being issued. Once the Program/Erase Controller has stopped the memory will be set to Read mode and the Erase will be suspended. If the Erase Suspend command is issued during the period when the memory is waiting for an additional block (before the Program/Erase Controller starts) then the Erase is suspended immediately and will start immediately when the Erase Resume Command is issued. It is not possible to select any further blocks to erase after the Erase Resume.

During Erase Suspend it is possible to Read and Program cells in blocks that are not being erased; both Read and Program operations behave as normal on these blocks. If any attempt is made to program in a protected block or in the suspended block then the Program command is ignored and the data remains unchanged. The Status Register is not read and no error condition is given. Reading from blocks that are being erased will output the Status Register.

It is also possible to issue the Auto Select, Read CFI Query and Unlock Bypass commands during an Erase Suspend. The Read/Reset command must be issued to return the device to Read Array mode before the Resume command will be accepted.

Erase Resume Command. The Erase Resume command must be used to restart the Program/Erase Controller from Erase Suspend. An erase can be suspended and resumed more than once.

Read CFI Query Command. The Read CFI Query Command is used to read data from the Common Flash Interface (CFI) Memory Area. This command is valid when the device is in the Read Array mode, or when the device is in Autoselected mode.

One Bus Write cycle is required to issue the Read CFI Query Command. Once the command is issued subsequent Bus Read operations read from the Common Flash Interface Memory Area.

The Read/Reset command must be issued to return the device to the previous mode (the Read Array mode or Autoselected mode). A second Read/Reset command would be needed if the device is to be put in the Read Array mode from Autoselected mode.

See Appendix B, Tables 21, 22, 23, 24, 25 and 26 for details on the information contained in the Common Flash Interface (CFI) memory area.

Table 4. Commands, 16-bit mode, $\overline{\text{BYTE}} = V_{IH}$

| Command | Length | Bus Write Operations | | | | | | | | | | | |
|-----------------------|--------|----------------------|------|------|------|------|------|------|------|------|------|------|------|
| | | 1st | | 2nd | | 3rd | | 4th | | 5th | | 6th | |
| | | Addr | Data | Addr | Data | Addr | Data | Addr | Data | Addr | Data | Addr | Data |
| Read/Reset | 1 | X | F0 | | | | | | | | | | |
| | 3 | 555 | AA | 2AA | 55 | X | F0 | | | | | | |
| Auto Select | 3 | 555 | AA | 2AA | 55 | 555 | 90 | | | | | | |
| Program | 4 | 555 | AA | 2AA | 55 | 555 | A0 | PA | PD | | | | |
| Unlock Bypass | 3 | 555 | AA | 2AA | 55 | 555 | 20 | | | | | | |
| Unlock Bypass Program | 2 | X | A0 | PA | PD | | | | | | | | |
| Unlock Bypass Reset | 2 | X | 90 | X | 00 | | | | | | | | |
| Chip Erase | 6 | 555 | AA | 2AA | 55 | 555 | 80 | 555 | AA | 2AA | 55 | 555 | 10 |
| Block Erase | 6+ | 555 | AA | 2AA | 55 | 555 | 80 | 555 | AA | 2AA | 55 | BA | 30 |
| Erase Suspend | 1 | X | B0 | | | | | | | | | | |
| Erase Resume | 1 | X | 30 | | | | | | | | | | |
| Read CFI Query | 1 | 55 | 98 | | | | | | | | | | |

Note: X Don't Care, PA Program Address, PD Program Data, BA Any address in the Block.

All values in the table are in hexadecimal.

The Command Interface only uses A-1, A0-A10 and DQ0-DQ7 to verify the commands; A11-A19, DQ8-DQ14 and DQ15 are Don't Care. DQ15A-1 is A-1 when $\overline{\text{BYTE}}$ is V_{IL} or DQ15 when $\overline{\text{BYTE}}$ is V_{IH} .

Read/Reset. After a Read/Reset command, read the memory as normal until another command is issued.

Auto Select. After an Auto Select command, read Manufacturer ID, Device ID or Block Protection Status.

Program, Unlock Bypass Program, Chip Erase, Block Erase. After these commands read the Status Register until the Program/Erase Controller completes and the memory returns to Read Mode. Add additional Blocks during Block Erase Command with additional Bus Write Operations until Timeout Bit is set.

Unlock Bypass. After the Unlock Bypass command issue Unlock Bypass Program or Unlock Bypass Reset commands.

Unlock Bypass Reset. After the Unlock Bypass Reset command read the memory as normal until another command is issued.

Erase Suspend. After the Erase Suspend command read non-erasing memory blocks as normal, issue Auto Select and Program commands on non-erasing blocks as normal.

Erase Resume. After the Erase Resume command the suspended Erase operation resumes, read the Status Register until the Program/Erase Controller completes and the memory returns to Read Mode.

CFI Query. Command is valid when device is ready to read array data or when device is in autoselected mode.

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Table 5. Commands, 8-bit mode, $\overline{\text{BYTE}} = \text{V}_{\text{IL}}$

| Command | Length | Bus Write Operations | | | | | | | | | | | |
|-----------------------|--------|----------------------|------|------|------|------|------|------|------|------|------|------|------|
| | | 1st | | 2nd | | 3rd | | 4th | | 5th | | 6th | |
| | | Addr | Data | Addr | Data | Addr | Data | Addr | Data | Addr | Data | Addr | Data |
| Read/Reset | 1 | X | F0 | | | | | | | | | | |
| | 3 | AAA | AA | 555 | 55 | X | F0 | | | | | | |
| Auto Select | 3 | AAA | AA | 555 | 55 | AAA | 90 | | | | | | |
| Program | 4 | AAA | AA | 555 | 55 | AAA | A0 | PA | PD | | | | |
| Unlock Bypass | 3 | AAA | AA | 555 | 55 | AAA | 20 | | | | | | |
| Unlock Bypass Program | 2 | X | A0 | PA | PD | | | | | | | | |
| Unlock Bypass Reset | 2 | X | 90 | X | 00 | | | | | | | | |
| Chip Erase | 6 | AAA | AA | 555 | 55 | AAA | 80 | AAA | AA | 555 | 55 | AAA | 10 |
| Block Erase | 6+ | AAA | AA | 555 | 55 | AAA | 80 | AAA | AA | 555 | 55 | BA | 30 |
| Erase Suspend | 1 | X | B0 | | | | | | | | | | |
| Erase Resume | 1 | X | 30 | | | | | | | | | | |
| Read CFI Query | 1 | AA | 98 | | | | | | | | | | |

Note: X Don't Care, PA Program Address, PD Program Data, BA Any address in the Block.

All values in the table are in hexadecimal.

The Command Interface only uses A-1, A0-A10 and DQ0-DQ7 to verify the commands; A11-A19, DQ8-DQ14 and DQ15 are Don't Care. DQ15A-1 is A-1 when $\overline{\text{BYTE}}$ is V_{IL} or DQ15 when $\overline{\text{BYTE}}$ is V_{IH} .

Read/Reset. After a Read/Reset command, read the memory as normal until another command is issued.

Auto Select. After an Auto Select command, read Manufacturer ID, Device ID or Block Protection Status.

Program, Unlock Bypass Program, Chip Erase, Block Erase. After these commands read the Status Register until the Program/Erase Controller completes and the memory returns to Read Mode. Add additional Blocks during Block Erase Command with additional Bus Write Operations until Timeout Bit is set.

Unlock Bypass. After the Unlock Bypass command issue Unlock Bypass Program or Unlock Bypass Reset commands.

Unlock Bypass Reset. After the Unlock Bypass Reset command read the memory as normal until another command is issued.

Erase Suspend. After the Erase Suspend command read non-erasing memory blocks as normal, issue Auto Select and Program commands on non-erasing blocks as normal.

Erase Resume. After the Erase Resume command the suspended Erase operation resumes, read the Status Register until the Program/Erase Controller completes and the memory returns to Read Mode.

CFI Query. Command is valid when device is ready to read array data or when device is in autoselected mode.

Table 6. Program, Erase Times and Program, Erase Endurance Cycles

| Parameter | Min | Typ ^(1,2) | Max ⁽²⁾ | Unit |
|----------------------------------|---------|----------------------|--------------------|--------|
| Chip Erase | | 29 | 120 ⁽³⁾ | s |
| Block Erase (64 KBytes) | | 0.8 | 6 ⁽⁴⁾ | s |
| Erase Suspend Latency Time | | 20 | 25 ⁽⁴⁾ | μs |
| Program (Byte or Word) | | 13 | 200 ⁽³⁾ | μs |
| Chip Program (Byte by Byte) | | 26 | 120 ⁽³⁾ | s |
| Chip Program (Word by Word) | | 13 | 60 ⁽³⁾ | s |
| Program/Erase Cycles (per Block) | 100,000 | | | cycles |
| Data Retention | 20 | | | years |

Note: 1. Typical values measured at room temperature and nominal voltages.

2. Sampled, but not 100% tested.

3. Maximum value measured at worst case conditions for both temperature and V_{CC} after 100,000 program/erase cycles .

4. Maximum value measured at worst case conditions for both temperature and V_{CC}.

STATUS REGISTER

Bus Read operations from any address always read the Status Register during Program and Erase operations. It is also read during Erase Suspend when an address within a block being erased is accessed.

The bits in the Status Register are summarized in Table 7, Status Register Bits.

Data Polling Bit (DQ7). The Data Polling Bit can be used to identify whether the Program/Erase Controller has successfully completed its operation or if it has responded to an Erase Suspend. The Data Polling Bit is output on DQ7 when the Status Register is read.

During Program operations the Data Polling Bit outputs the complement of the bit being programmed to DQ7. After successful completion of the Program operation the memory returns to Read mode and Bus Read operations from the address just programmed output DQ7, not its complement.

During Erase operations the Data Polling Bit outputs '0', the complement of the erased state of DQ7. After successful completion of the Erase operation the memory returns to Read Mode.

In Erase Suspend mode the Data Polling Bit will output a '1' during a Bus Read operation within a block being erased. The Data Polling Bit will change from a '0' to a '1' when the Program/Erase Controller has suspended the Erase operation.

Figure 7, Data Polling Flowchart, gives an example of how to use the Data Polling Bit. A Valid Address is the address being programmed or an address within the block being erased.

Toggle Bit (DQ6). The Toggle Bit can be used to identify whether the Program/Erase Controller has successfully completed its operation or if it has responded to an Erase Suspend. The Toggle Bit is output on DQ6 when the Status Register is read.

During Program and Erase operations the Toggle Bit changes from '0' to '1' to '0', etc., with successive Bus Read operations at any address. After successful completion of the operation the memory returns to Read mode.

During Erase Suspend mode the Toggle Bit will output when addressing a cell within a block being erased. The Toggle Bit will stop toggling when the Program/Erase Controller has suspended the Erase operation.

If any attempt is made to erase a protected block, the operation is aborted, no error is signalled and DQ6 toggles for approximately 100μs. If any attempt is made to program a protected block or a suspended block, the operation is aborted, no error is signalled and DQ6 toggles for approximately 1μs.

Figure 8, Data Toggle Flowchart, gives an example of how to use the Data Toggle Bit.

Error Bit (DQ5). The Error Bit can be used to identify errors detected by the Program/Erase Controller. The Error Bit is set to '1' when a Program, Block Erase or Chip Erase operation fails to write the correct data to the memory. If the Error Bit is set a Read/Reset command must be issued before other commands are issued. The Error bit is output on DQ5 when the Status Register is read.

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Note that the Program command cannot change a bit set to '0' back to '1' and attempting to do so will set DQ5 to '1'. A Bus Read operation to that address will show the bit is still '0'. One of the Erase commands must be used to set all the bits in a block or in the whole memory from '0' to '1'.

Erase Timer Bit (DQ3). The Erase Timer Bit can be used to identify the start of Program/Erase Controller operation during a Block Erase command. Once the Program/Erase Controller starts erasing the Erase Timer Bit is set to '1'. Before the Program/Erase Controller starts the Erase Timer Bit is set to '0' and additional blocks to be erased may be written to the Command Interface. The Erase Timer Bit is output on DQ3 when the Status Register is read.

Alternative Toggle Bit (DQ2). The Alternative Toggle Bit can be used to monitor the Program/Erase controller during Erase operations. The Alternative Toggle Bit is output on DQ2 when the Status Register is read.

During Chip Erase and Block Erase operations the Toggle Bit changes from '0' to '1' to '0', etc., with successive Bus Read operations from addresses within the blocks being erased. A protected block is treated the same as a block not being erased. Once the operation completes the memory returns to Read mode.

During Erase Suspend the Alternative Toggle Bit changes from '0' to '1' to '0', etc. with successive Bus Read operations from addresses within the blocks being erased. Bus Read operations to addresses within blocks not being erased will output the memory cell data as if in Read mode.

After an Erase operation that causes the Error Bit to be set the Alternative Toggle Bit can be used to identify which block or blocks have caused the error. The Alternative Toggle Bit changes from '0' to '1' to '0', etc. with successive Bus Read Operations from addresses within blocks that have not erased correctly. The Alternative Toggle Bit does not change if the addressed block has erased correctly.

Table 7. Status Register Bits

| Operation | Address | DQ7 | DQ6 | DQ5 | DQ3 | DQ2 | R \bar{B} |
|------------------------------|----------------------|---------------------|-----------|-----|-----|-----------|-------------|
| Program | Any Address | $\overline{DQ7}$ | Toggle | 0 | – | – | 0 |
| Program During Erase Suspend | Any Address | $\overline{DQ7}$ | Toggle | 0 | – | – | 0 |
| Program Error | Any Address | $\overline{DQ7}$ | Toggle | 1 | – | – | 0 |
| Chip Erase | Any Address | 0 | Toggle | 0 | 1 | Toggle | 0 |
| Block Erase before timeout | Erasing Block | 0 | Toggle | 0 | 0 | Toggle | 0 |
| | Non-Erasing Block | 0 | Toggle | 0 | 0 | No Toggle | 0 |
| Block Erase | Erasing Block | 0 | Toggle | 0 | 1 | Toggle | 0 |
| | Non-Erasing Block | 0 | Toggle | 0 | 1 | No Toggle | 0 |
| Erase Suspend | Erasing Block | 1 | No Toggle | 0 | – | Toggle | 1 |
| | Non-Erasing Block | Data read as normal | | | | | |
| Erase Error | Good Block Address | 0 | Toggle | 1 | 1 | No Toggle | 0 |
| | Faulty Block Address | 0 | Toggle | 1 | 1 | Toggle | 0 |

Note: Unspecified data bits should be ignored.

Figure 7. Data Polling Flowchart

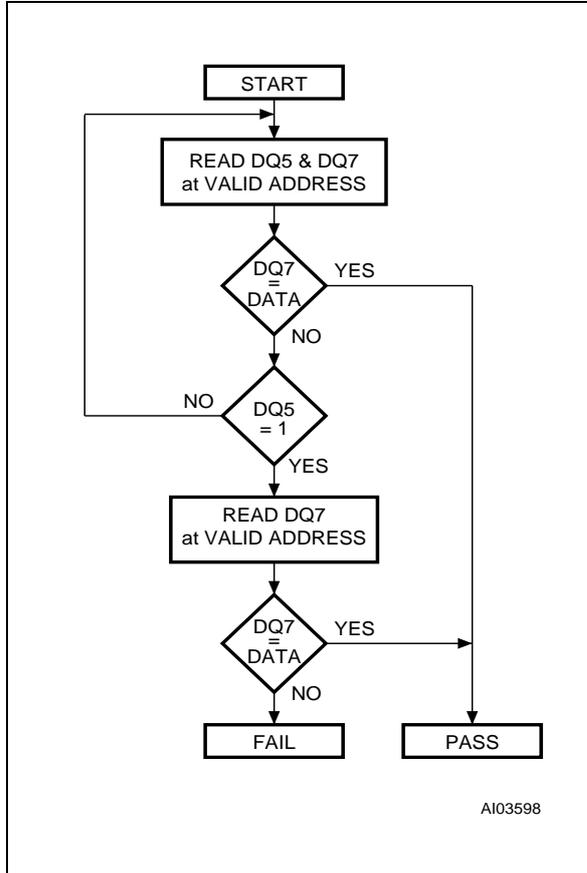
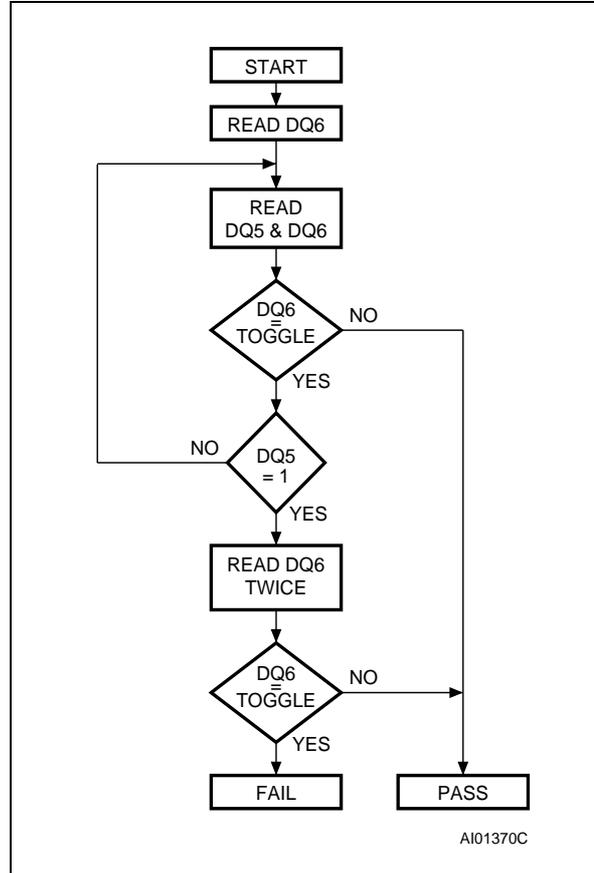


Figure 8. Data Toggle Flowchart



MAXIMUM RATING

Stressing the device above the rating listed in the Absolute Maximum Ratings" table may cause permanent damage to the device. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. These are stress ratings only and operation of the device at

these or any other conditions above those indicated in the Operating sections of this specification is not implied. Refer also to the STMicroelectronics SURE Program and other relevant quality documents.

Table 8. Absolute Maximum Ratings

| Symbol | Parameter | Min | Max | Unit |
|-------------------|--|------|----------------------|------|
| T _{BIAS} | Temperature Under Bias | -50 | 125 | °C |
| T _{STG} | Storage Temperature | -65 | 150 | °C |
| V _{IO} | Input or Output Voltage ^(1,2) | -0.6 | V _{CC} +0.6 | V |
| V _{CC} | Supply Voltage | -0.6 | 4 | V |
| V _{ID} | Identification Voltage | -0.6 | 13.5 | V |

Note: 1. Minimum voltage may undershoot to -2V during transition and for less than 20ns during transitions.
 2. Maximum voltage may overshoot to V_{CC} +2V during transition and for less than 20ns during transitions.

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DC AND AC PARAMETERS

This section summarizes the operating measurement conditions, and the DC and AC characteristics of the device. The parameters in the DC and AC characteristics Tables that follow, are derived from tests performed under the Measurement

Conditions summarized in Table 9, Operating and AC Measurement Conditions. Designers should check that the operating conditions in their circuit match the operating conditions when relying on the quoted parameters.

Table 9. Operating and AC Measurement Conditions

| Parameter | M29W160E | | | | Unit |
|---------------------------------------|----------------------|-----|----------------------|-----|------|
| | 70 | | 90 | | |
| | Min | Max | Min | Max | |
| V _{CC} Supply Voltage | 2.7 | 3.6 | 2.7 | 3.6 | V |
| Ambient Operating Temperature | -40 | 85 | -40 | 85 | °C |
| Load Capacitance (C _L) | 30 | | 30 | | pF |
| Input Rise and Fall Times | | 10 | | 10 | ns |
| Input Pulse Voltages | 0 to V _{CC} | | 0 to V _{CC} | | V |
| Input and Output Timing Ref. Voltages | V _{CC} /2 | | V _{CC} /2 | | V |

Figure 9. AC Measurement I/O Waveform

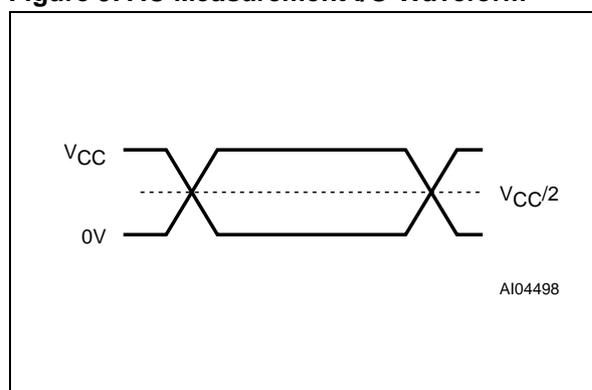


Figure 10. AC Measurement Load Circuit

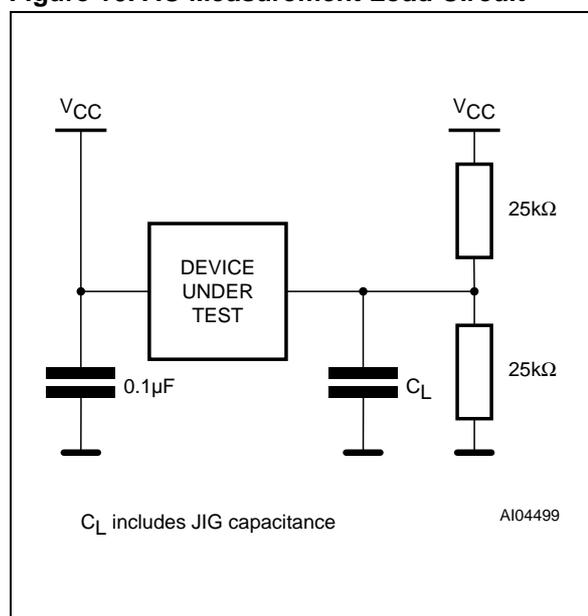


Table 10. Device Capacitance

| Symbol | Parameter | Test Condition | Min | Max | Unit |
|------------------|--------------------|-----------------------|-----|-----|------|
| C _{IN} | Input Capacitance | V _{IN} = 0V | | 6 | pF |
| C _{OUT} | Output Capacitance | V _{OUT} = 0V | | 12 | pF |

Note: Sampled only, not 100% tested.

Table 11. DC Characteristics

| Symbol | Parameter | Test Condition | Min | Typ | Max | Unit |
|-----------------|--------------------------------------|--|----------------|-----|----------------|---------|
| I_{LI} | Input Leakage Current | $0V \leq V_{IN} \leq V_{CC}$ | | | ± 1 | μA |
| I_{LO} | Output Leakage Current | $0V \leq V_{OUT} \leq V_{CC}$ | | | ± 1 | μA |
| I_{CC1} | Supply Current (Read) | $\bar{E} = V_{IL}, \bar{G} = V_{IH},$ $f = 6MHz$ | | 4.5 | 10 | mA |
| I_{CC2} | Supply Current (Standby) | $\bar{E} = V_{CC} \pm 0.2V,$ $\bar{RP} = V_{CC} \pm 0.2V$ | | 35 | 100 | μA |
| $I_{CC3}^{(1)}$ | Supply Current (Program/Erase) | Program/Erase Controller active | | | 20 | mA |
| V_{IL} | Input Low Voltage | | -0.5 | | 0.8 | V |
| V_{IH} | Input High Voltage | | $0.7V_{CC}$ | | $V_{CC} + 0.3$ | V |
| V_{OL} | Output Low Voltage | $I_{OL} = 1.8mA$ | | | 0.45 | V |
| V_{OH} | Output High Voltage | $I_{OH} = -100\mu A$ | $V_{CC} - 0.4$ | | | V |
| V_{ID} | Identification Voltage | | 11.5 | | 12.5 | V |
| I_{ID} | Identification Current | $A9 = V_{ID}$ | | | 100 | μA |
| V_{LKO} | Program/Erase Lockout Supply Voltage | | 1.8 | | 2.3 | V |

Note: 1. Sampled only, not 100% tested.

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Figure 11. Read Mode AC Waveforms

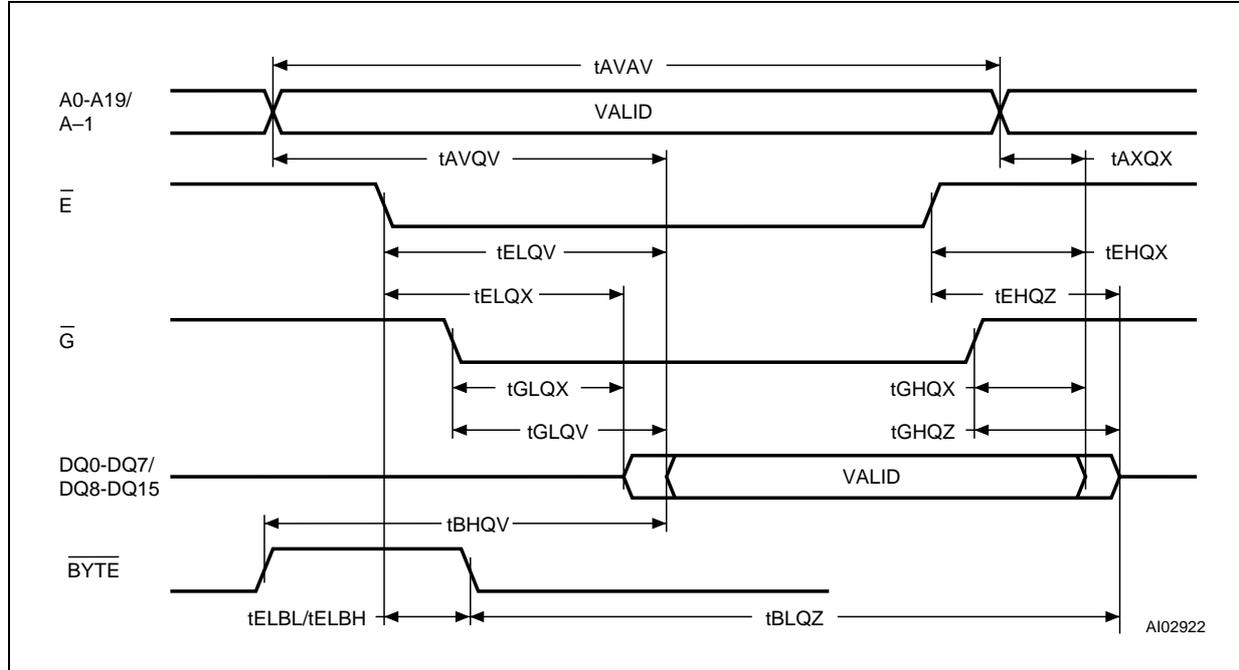


Table 12. Read AC Characteristics

| Symbol | Alt | Parameter | Test Condition | | M29W160E | | Unit |
|--|--------------------------|---|--|-----|----------|----|------|
| | | | | | 70 | 90 | |
| t_{AVAV} | t_{RC} | Address Valid to Next Address Valid | $\bar{E} = V_{IL}$, $\bar{G} = V_{IL}$ | Min | 70 | 90 | ns |
| t_{AVQV} | t_{ACC} | Address Valid to Output Valid | $\bar{E} = V_{IL}$, $\bar{G} = V_{IL}$ | Max | 70 | 90 | ns |
| $t_{ELQX}^{(1)}$ | t_{LZ} | Chip Enable Low to Output Transition | $\bar{G} = V_{IL}$ | Min | 0 | 0 | ns |
| t_{ELQV} | t_{CE} | Chip Enable Low to Output Valid | $\bar{G} = V_{IL}$ | Max | 70 | 90 | ns |
| $t_{GLQX}^{(1)}$ | t_{OLZ} | Output Enable Low to Output Transition | $\bar{E} = V_{IL}$ | Min | 0 | 0 | ns |
| t_{GLQV} | t_{OE} | Output Enable Low to Output Valid | $\bar{E} = V_{IL}$ | Max | 30 | 35 | ns |
| $t_{EHQZ}^{(1)}$ | t_{HZ} | Chip Enable High to Output Hi-Z | $\bar{G} = V_{IL}$ | Max | 25 | 30 | ns |
| $t_{GHQZ}^{(1)}$ | t_{DF} | Output Enable High to Output Hi-Z | $\bar{E} = V_{IL}$ | Max | 25 | 30 | ns |
| t_{EHQX} t_{GHQX} t_{AXQX} | t_{OH} | Chip Enable, Output Enable or Address Transition to Output Transition | | Min | 0 | 0 | ns |
| t_{ELBL} t_{ELBH} | t_{ELFL} t_{ELFH} | Chip Enable to $\overline{\text{BYTE}}$ Low or High | | Max | 5 | 5 | ns |
| t_{BLQZ} | t_{FLQZ} | $\overline{\text{BYTE}}$ Low to Output Hi-Z | | Max | 25 | 30 | ns |
| t_{BHQV} | t_{FHQV} | $\overline{\text{BYTE}}$ High to Output Valid | | Max | 30 | 40 | ns |

Note: 1. Sampled only, not 100% tested.

Figure 12. Write AC Waveforms, Write Enable Controlled

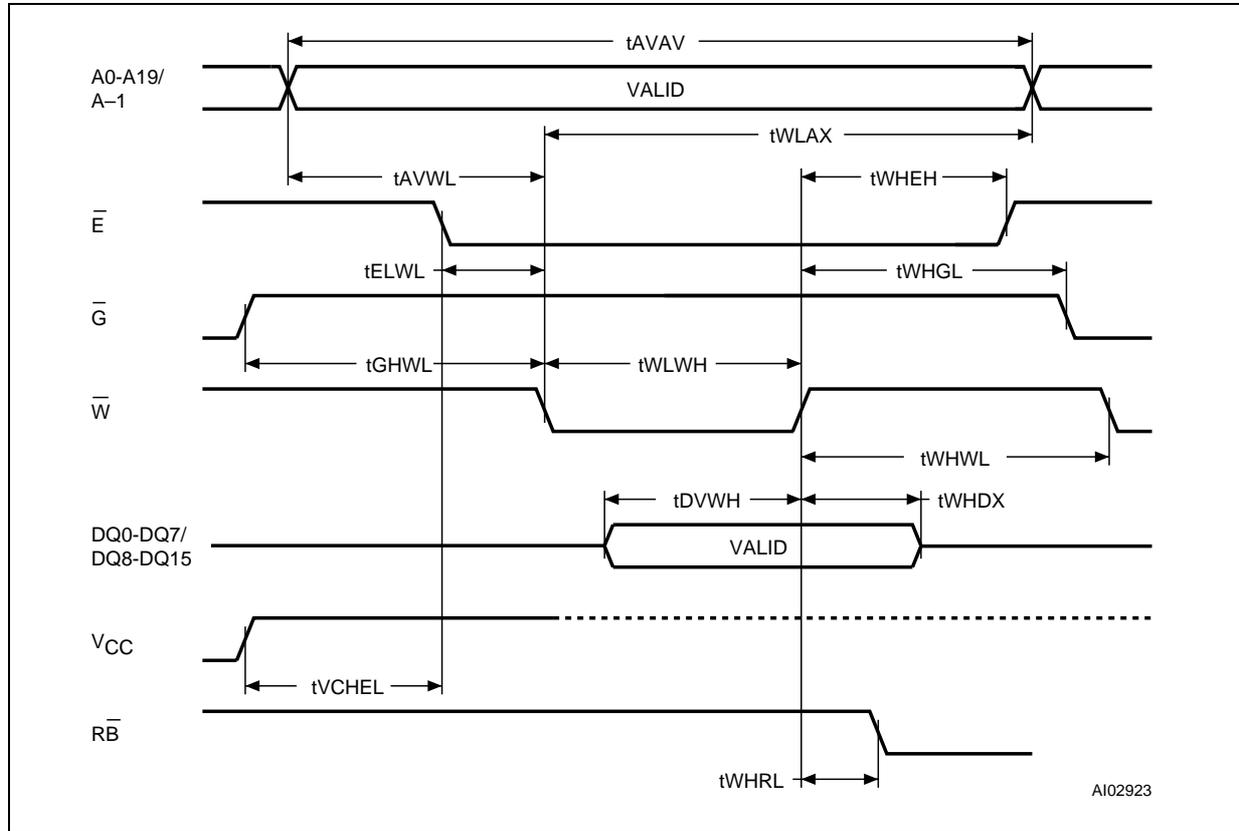


Table 13. Write AC Characteristics, Write Enable Controlled

| Symbol | Alt | Parameter | | M29W160E | | Unit |
|----------------------|-------|--|-----|----------|----|------|
| | | | | 70 | 90 | |
| tAVAV | tWC | Address Valid to Next Address Valid | Min | 70 | 90 | ns |
| tELWL | tCS | Chip Enable Low to Write Enable Low | Min | 0 | 0 | ns |
| tWLWH | tWP | Write Enable Low to Write Enable High | Min | 45 | 50 | ns |
| tDVWH | tDS | Input Valid to Write Enable High | Min | 45 | 50 | ns |
| tWHDX | tDH | Write Enable High to Input Transition | Min | 0 | 0 | ns |
| tWHEH | tCH | Write Enable High to Chip Enable High | Min | 0 | 0 | ns |
| tWHWL | tWPH | Write Enable High to Write Enable Low | Min | 30 | 30 | ns |
| tAVWL | tAS | Address Valid to Write Enable Low | Min | 0 | 0 | ns |
| tWLAX | tAH | Write Enable Low to Address Transition | Min | 45 | 50 | ns |
| tGHWL | | Output Enable High to Write Enable Low | Min | 0 | 0 | ns |
| tWHGL | tOEHL | Write Enable High to Output Enable Low | Min | 0 | 0 | ns |
| tWHRL ⁽¹⁾ | tBUSY | Program/Erase Valid to RB-bar Low | Max | 30 | 35 | ns |
| tVCHL | tVCS | VCC High to Chip Enable Low | Min | 50 | 50 | µs |

Note: 1. Sampled only, not 100% tested.

Figure 14. Reset/Block Temporary Unprotect AC Waveforms

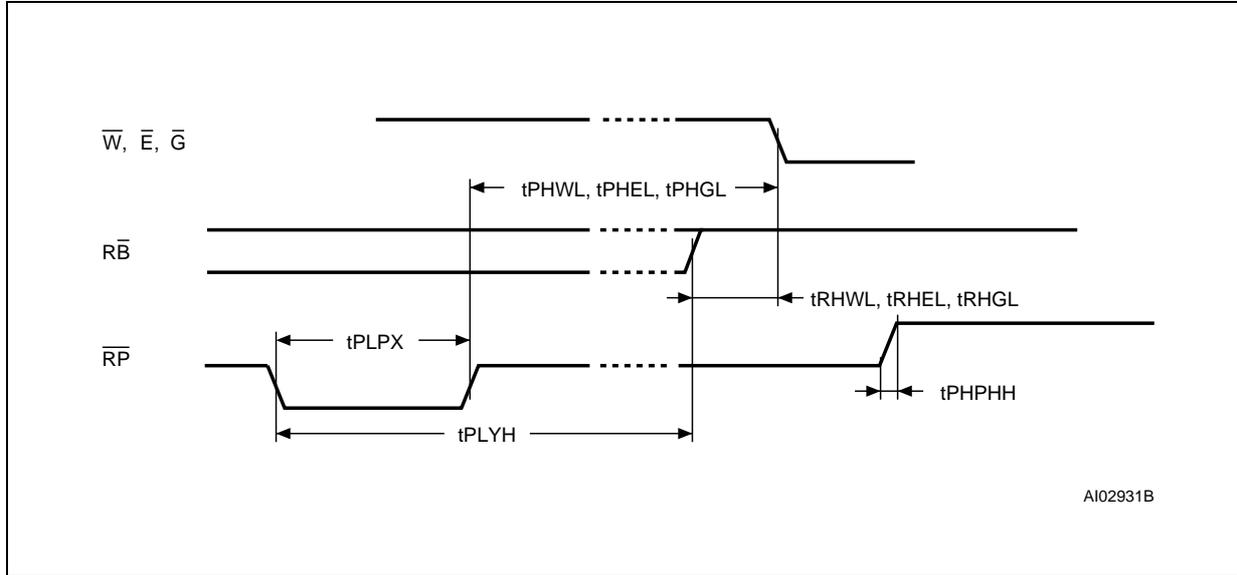


Table 15. Reset/Block Temporary Unprotect AC Characteristics

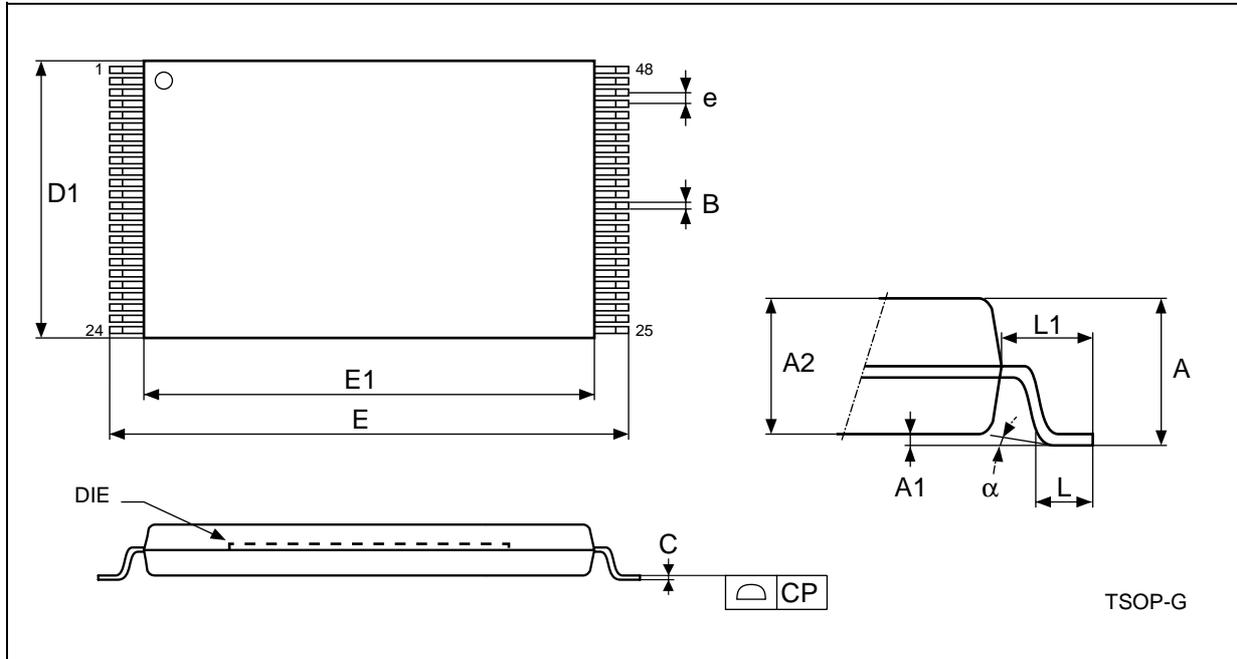
| Symbol | Alt | Parameter | M29W160E | | Unit | |
|--|-------------|--|----------|-----|------|---------|
| | | | 70 | 90 | | |
| $t_{PHWL}^{(1)}$ $t_{PHEL}^{(1)}$ $t_{PHGL}^{(1)}$ | t_{RH} | \overline{RP} High to Write Enable Low, Chip Enable Low, Output Enable Low | Min | 50 | 50 | ns |
| $t_{RHWL}^{(1)}$ $t_{RHEL}^{(1)}$ $t_{RHGL}^{(1)}$ | t_{RB} | \overline{RB} High to Write Enable Low, Chip Enable Low, Output Enable Low | Min | 0 | 0 | ns |
| t_{PLPX} | t_{RP} | \overline{RP} Pulse Width | Min | 500 | 500 | ns |
| $t_{PLYH}^{(1)}$ | t_{READY} | \overline{RP} Low to Read Mode | Max | 10 | 10 | μ s |
| $t_{PHPHH}^{(1)}$ | t_{VIDR} | \overline{RP} Rise Time to V_{ID} | Min | 500 | 500 | ns |

Note: 1. Sampled only, not 100% tested.

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PACKAGE MECHANICAL

Figure 15. TSOP48 – 48 lead Plastic Thin Small Outline, 12 x 20mm, Package Outline

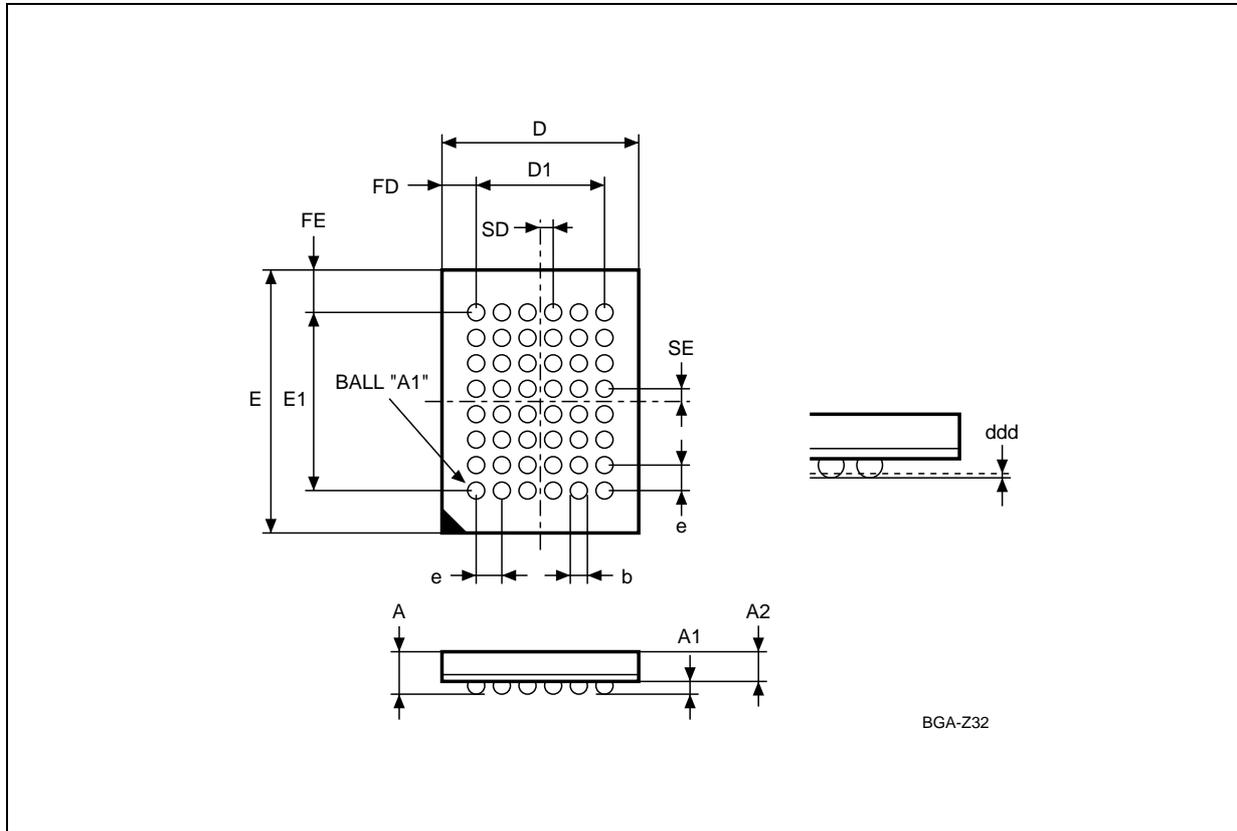


Note: Drawing is not to scale.

Table 16. TSOP48 – 48 lead Plastic Thin Small Outline, 12 x 20mm, Package Mechanical Data

| Symbol | millimeters | | | inches | | |
|----------|-------------|--------|--------|--------|--------|--------|
| | Typ | Min | Max | Typ | Min | Max |
| A | | | 1.200 | | | 0.0472 |
| A1 | 0.100 | 0.050 | 0.150 | 0.0039 | 0.0020 | 0.0059 |
| A2 | 1.000 | 0.950 | 1.050 | 0.0394 | 0.0374 | 0.0413 |
| B | 0.220 | 0.170 | 0.270 | 0.0087 | 0.0067 | 0.0106 |
| C | | 0.100 | 0.210 | | 0.0039 | 0.0083 |
| CP | | | 0.080 | | | 0.0031 |
| D1 | 12.000 | 11.900 | 12.100 | 0.4724 | 0.4685 | 0.4764 |
| E | 20.000 | 19.800 | 20.200 | 0.7874 | 0.7795 | 0.7953 |
| E1 | 18.400 | 18.300 | 18.500 | 0.7244 | 0.7205 | 0.7283 |
| e | 0.500 | – | – | 0.0197 | – | – |
| L | 0.600 | 0.500 | 0.700 | 0.0236 | 0.0197 | 0.0276 |
| L1 | 0.800 | | | 0.0315 | | |
| α | 3 | 0 | 5 | 3 | 0 | 5 |

Figure 16. TFBGA48 6x8mm - 6x8 ball array, 0.80 mm pitch, Package Outline



BGA-Z32

Table 17. TFBGA48 6x8mm - 6x8 ball array, 0.80 mm pitch, Package Mechanical Data

| Symbol | millimeters | | | inches | | |
|--------|-------------|-------|-------|--------|--------|--------|
| | Typ | Min | Max | Typ | Min | Max |
| A | | | 1.200 | | | 0.0472 |
| A1 | | 0.260 | | | 0.0102 | |
| A2 | | | 0.900 | | | 0.0354 |
| b | | 0.350 | 0.450 | | 0.0138 | 0.0177 |
| D | 6.000 | 5.900 | 6.100 | 0.2362 | 0.2323 | 0.2402 |
| D1 | 4.000 | – | – | 0.1575 | – | – |
| ddd | | | 0.100 | | | 0.0039 |
| E | 8.000 | 7.900 | 8.100 | 0.3150 | 0.3110 | 0.3189 |
| E1 | 5.600 | – | – | 0.2205 | – | – |
| e | 0.800 | – | – | 0.0315 | – | – |
| FD | 1.000 | – | – | 0.0394 | – | – |
| FE | 1.200 | – | – | 0.0472 | – | – |
| SD | 0.400 | – | – | 0.0157 | – | – |
| SE | 0.400 | – | – | 0.0157 | – | – |

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PART NUMBERING

Table 18. Ordering Information Scheme

| | | | | | |
|---|-----------|----|---|---|---|
| Example: | M29W160EB | 90 | N | 6 | T |
| Device Type M29 | | | | | |
| Operating Voltage W = V _{CC} = 2.7 to 3.6V | | | | | |
| Device Function 160E = 16 Mbit (x8/x16), Boot Block | | | | | |
| Array Matrix T = Top Boot B = Bottom Boot | | | | | |
| Speed 70 = 70 ns 90 = 90 ns | | | | | |
| Package N = TSOP48: 12 x 20 mm ZA = TFBGA48: 6x8 mm, 0.80mm pitch | | | | | |
| Temperature Range 6 = -40 to 85 °C | | | | | |
| Option Blank = Standard Packing T = Tape and Reel Packing E = Lead-free Package, Standard Packing F = Lead-free Package, Tape & Reel Packing | | | | | |

Devices are shipped from the factory with the memory content bits erased to '1'.

For a list of available options (Speed, Package, etc.) or for further information on any aspect of this device, please contact the ST Sales Office nearest to you.

APPENDIX A. BLOCK ADDRESS TABLE

Table 19. Top Boot Block Addresses, M29W160ET

| # | Size (KBytes) | Address Range (x8) | Address Range (x16) |
|----|---------------|--------------------|---------------------|
| 34 | 16 | 1FC000h-1FFFFFFh | FE000h-FFFFFFh |
| 33 | 8 | 1FA000h-1FBFFFh | FD000h-FDFFFh |
| 32 | 8 | 1F8000h-1F9FFFh | FC000h-FCFFFh |
| 31 | 32 | 1F0000h-1F7FFFh | F8000h-FBFFFh |
| 30 | 64 | 1E0000h-1EFFFFh | F0000h-F7FFFh |
| 29 | 64 | 1D0000h-1DFFFFh | E8000h-EFFFFh |
| 28 | 64 | 1C0000h-1CFFFFh | E0000h-E7FFFh |
| 27 | 64 | 1B0000h-1BFFFFh | D8000h-DFFFFh |
| 26 | 64 | 1A0000h-1AFFFFh | D0000h-D7FFFh |
| 25 | 64 | 190000h-19FFFFh | C8000h-CFFFFh |
| 24 | 64 | 180000h-18FFFFh | C0000h-C7FFFh |
| 23 | 64 | 170000h-17FFFFh | B8000h-BFFFFh |
| 22 | 64 | 160000h-16FFFFh | B0000h-B7FFFh |
| 21 | 64 | 150000h-15FFFFh | A8000h-AFFFFh |
| 20 | 64 | 140000h-14FFFFh | A0000h-A7FFFh |
| 19 | 64 | 130000h-13FFFFh | 98000h-9FFFFh |
| 18 | 64 | 120000h-12FFFFh | 90000h-97FFFh |
| 17 | 64 | 110000h-11FFFFh | 88000h-8FFFFh |
| 16 | 64 | 100000h-10FFFFh | 80000h-87FFFh |
| 15 | 64 | 0F0000h-0FFFFFFh | 78000h-7FFFFh |
| 14 | 64 | 0E0000h-0EFFFFh | 70000h-77FFFh |
| 13 | 64 | 0D0000h-0DFFFFh | 68000h-6FFFFh |
| 12 | 64 | 0C0000h-0CFFFFh | 60000h-67FFFh |
| 11 | 64 | 0B0000h-0BFFFFh | 58000h-5FFFFh |
| 10 | 64 | 0A0000h-0AFFFFh | 50000h-57FFFh |
| 9 | 64 | 090000h-09FFFFh | 48000h-4FFFFh |
| 8 | 64 | 080000h-08FFFFh | 40000h-47FFFh |
| 7 | 64 | 070000h-07FFFFh | 38000h-3FFFFh |
| 6 | 64 | 060000h-06FFFFh | 30000h-37FFFh |
| 5 | 64 | 050000h-05FFFFh | 28000h-2FFFFh |
| 4 | 64 | 040000h-04FFFFh | 20000h-27FFFh |
| 3 | 64 | 030000h-03FFFFh | 18000h-1FFFFh |
| 2 | 64 | 020000h-02FFFFh | 10000h-17FFFh |
| 1 | 64 | 010000h-01FFFFh | 08000h-0FFFFh |
| 0 | 64 | 000000h-00FFFFh | 00000h-07FFFh |

Table 20. Bottom Boot Block Addresses, M29W160EB

| # | Size (KBytes) | Address Range (x8) | Address Range (x16) |
|----|---------------|--------------------|---------------------|
| 34 | 64 | 1F0000h-1FFFFFFh | F8000h-FFFFFFh |
| 33 | 64 | 1E0000h-1EFFFFh | F0000h-F7FFFh |
| 32 | 64 | 1D0000h-1DFFFFh | E8000h-EFFFFh |
| 31 | 64 | 1C0000h-1CFFFFh | E0000h-E7FFFh |
| 30 | 64 | 1B0000h-1BFFFFh | D8000h-DFFFFh |
| 29 | 64 | 1A0000h-1AFFFFh | D0000h-D7FFFh |
| 28 | 64 | 190000h-19FFFFh | C8000h-CFFFFh |
| 27 | 64 | 180000h-18FFFFh | C0000h-C7FFFh |
| 26 | 64 | 170000h-17FFFFh | B8000h-BFFFFh |
| 25 | 64 | 160000h-16FFFFh | B0000h-B7FFFh |
| 24 | 64 | 150000h-15FFFFh | A8000h-AFFFFh |
| 23 | 64 | 140000h-14FFFFh | A0000h-A7FFFh |
| 22 | 64 | 130000h-13FFFFh | 98000h-9FFFFh |
| 21 | 64 | 120000h-12FFFFh | 90000h-97FFFh |
| 20 | 64 | 110000h-11FFFFh | 88000h-8FFFFh |
| 19 | 64 | 100000h-10FFFFh | 80000h-87FFFh |
| 18 | 64 | 0F0000h-0FFFFFFh | 78000h-7FFFFh |
| 17 | 64 | 0E0000h-0EFFFFh | 70000h-77FFFh |
| 16 | 64 | 0D0000h-0DFFFFh | 68000h-6FFFFh |
| 15 | 64 | 0C0000h-0CFFFFh | 60000h-67FFFh |
| 14 | 64 | 0B0000h-0BFFFFh | 58000h-5FFFFh |
| 13 | 64 | 0A0000h-0AFFFFh | 50000h-57FFFh |
| 12 | 64 | 090000h-09FFFFh | 48000h-4FFFFh |
| 11 | 64 | 080000h-08FFFFh | 40000h-47FFFh |
| 10 | 64 | 070000h-07FFFFh | 38000h-3FFFFh |
| 9 | 64 | 060000h-06FFFFh | 30000h-37FFFh |
| 8 | 64 | 050000h-05FFFFh | 28000h-2FFFFh |
| 7 | 64 | 040000h-04FFFFh | 20000h-27FFFh |
| 6 | 64 | 030000h-03FFFFh | 18000h-1FFFFh |
| 5 | 64 | 020000h-02FFFFh | 10000h-17FFFh |
| 4 | 64 | 010000h-01FFFFh | 08000h-0FFFFh |
| 3 | 32 | 008000h-00FFFFh | 04000h-07FFFh |
| 2 | 8 | 006000h-007FFFh | 03000h-03FFFh |
| 1 | 8 | 004000h-005FFFh | 02000h-02FFFh |
| 0 | 16 | 000000h-003FFFh | 00000h-01FFFh |

APPENDIX B. COMMON FLASH INTERFACE (CFI)

The Common Flash Interface is a JEDEC approved, standardized data structure that can be read from the Flash memory device. It allows a system software to query the device to determine various electrical and timing parameters, density information and functions supported by the memory. The system can interface easily with the device, enabling the software to upgrade itself when necessary.

When the CFI Query Command is issued the device enters CFI Query mode and the data structure is read from the memory. Tables 21, 22, 23, 24, 25

and 26 show the addresses used to retrieve the data.

The CFI data structure also contains a security area where a 64 bit unique security number is written (see Table 26, Security Code area). This area can be accessed only in Read mode by the final user. It is impossible to change the security number after it has been written by ST. Issue a Read command to return to Read mode.

Note: The Common Flash Interface is only available for Temperature range 6 (-40 to 85°C).

Table 21. Query Structure Overview

| Address | | Sub-section Name | Description |
|---------|-----|---|---|
| x16 | x8 | | |
| 10h | 20h | CFI Query Identification String | Command set ID and algorithm data offset |
| 1Bh | 36h | System Interface Information | Device timing & voltage information |
| 27h | 4Eh | Device Geometry Definition | Flash device layout |
| 40h | 80h | Primary Algorithm-specific Extended Query table | Additional information specific to the Primary Algorithm (optional) |
| 61h | C2h | Security Code Area | 64 bit unique device number |

Note: Query data are always presented on the lowest order data outputs.

Table 22. CFI Query Identification String

| Address | | Data | Description | Value |
|---------|-----|-------|--|----------------|
| x16 | x8 | | | |
| 10h | 20h | 0051h | Query Unique ASCII String "QRY" | "Q" |
| 11h | 22h | 0052h | | "R" |
| 12h | 24h | 0059h | | "Y" |
| 13h | 26h | 0002h | Primary Algorithm Command Set and Control Interface ID code 16 bit ID code defining a specific algorithm | AMD Compatible |
| 14h | 28h | 0000h | | |
| 15h | 2Ah | 0040h | Address for Primary Algorithm extended Query table (see Table 24) | P = 40h |
| 16h | 2Ch | 0000h | | |
| 17h | 2Eh | 0000h | Alternate Vendor Command Set and Control Interface ID Code second vendor - specified algorithm supported | NA |
| 18h | 30h | 0000h | | |
| 19h | 32h | 0000h | Address for Alternate Algorithm extended Query table | NA |
| 1Ah | 34h | 0000h | | |

Note: Query data are always presented on the lowest order data outputs (DQ7-DQ0) only. DQ8-DQ15 are '0'.

Table 23. CFI Query System Interface Information

| Address | | Data | Description | Value |
|---------|-----|-------|---|-------|
| x16 | x8 | | | |
| 1Bh | 36h | 0027h | V _{CC} Logic Supply Minimum Program/Erase voltage bit 7 to 4 BCD value in volts bit 3 to 0 BCD value in 100 mV | 2.7V |
| 1Ch | 38h | 0036h | V _{CC} Logic Supply Maximum Program/Erase voltage bit 7 to 4 BCD value in volts bit 3 to 0 BCD value in 100 mV | 3.6V |
| 1Dh | 3Ah | 0000h | V _{PP} [Programming] Supply Minimum Program/Erase voltage | NA |
| 1Eh | 3Ch | 0000h | V _{PP} [Programming] Supply Maximum Program/Erase voltage | NA |
| 1Fh | 3Eh | 0004h | Typical timeout per single Byte/Word program = 2 ⁿ μs | 16μs |
| 20h | 40h | 0000h | Typical timeout for minimum size write buffer program = 2 ⁿ μs | NA |
| 21h | 42h | 000Ah | Typical timeout per individual block erase = 2 ⁿ ms | 1s |
| 22h | 44h | 0000h | Typical timeout for full chip erase = 2 ⁿ ms | NA |
| 23h | 46h | 0004h | Maximum timeout for Byte/Word program = 2 ⁿ times typical | 256μs |
| 24h | 48h | 0000h | Maximum timeout for write buffer program = 2 ⁿ times typical | NA |
| 25h | 4Ah | 0003h | Maximum timeout per individual block erase = 2 ⁿ times typical | 8s |
| 26h | 4Ch | 0000h | Maximum timeout for chip erase = 2 ⁿ times typical | NA |

M29W160ET, M29W160EB

Table 24. Device Geometry Definition

| Address | | Data | Description | Value |
|------------|------------|----------------|---|-------------------|
| x16 | x8 | | | |
| 27h | 4Eh | 0015h | Device Size = 2 ⁿ in number of Bytes | 2 MByte |
| 28h 29h | 50h 52h | 0002h 0000h | Flash Device Interface Code description | x8, x16 Async. |
| 2Ah 2Bh | 54h 56h | 0000h 0000h | Maximum number of Bytes in multi-Byte program or page = 2 ⁿ | NA |
| 2Ch | 58h | 0004h | Number of Erase Block Regions within the device. It specifies the number of regions within the device containing contiguous Erase Blocks of the same size. | 4 |
| 2Dh 2Eh | 5Ah 5Ch | 0000h 0000h | Region 1 Information Number of identical size erase block = 0000h+1 | 1 |
| 2Fh 30h | 5Eh 60h | 0040h 0000h | Region 1 Information Block size in Region 1 = 0040h * 256 Byte | 16 KByte |
| 31h 32h | 62h 64h | 0001h 0000h | Region 2 Information Number of identical size erase block = 0001h+1 | 2 |
| 33h 34h | 66h 68h | 0020h 0000h | Region 2 Information Block size in Region 2 = 0020h * 256 Byte | 8 KByte |
| 35h 36h | 6Ah 6Ch | 0000h 0000h | Region 3 Information Number of identical size erase block = 0000h+1 | 1 |
| 37h 38h | 6Eh 70h | 0080h 0000h | Region 3 Information Block size in Region 3 = 0080h * 256 Byte | 32 KByte |
| 39h 3Ah | 72h 74h | 001Eh 0000h | Region 4 Information Number of identical-size erase block = 001Eh+1 | 31 |
| 3Bh 3Ch | 76h 78h | 0000h 0001h | Region 4 Information Block size in Region 4 = 0100h * 256 Byte | 64 KByte |

Table 25. Primary Algorithm-Specific Extended Query Table

| Address | | Data | Description | Value |
|---------|-----|-------|---|-------|
| x16 | x8 | | | |
| 40h | 80h | 0050h | Primary Algorithm extended Query table unique ASCII string "PRI" | "P" |
| 41h | 82h | 0052h | | "R" |
| 42h | 84h | 0049h | | "I" |
| 43h | 86h | 0031h | Major version number, ASCII | "1" |
| 44h | 88h | 0030h | Minor version number, ASCII | "0" |
| 45h | 8Ah | 0000h | Address Sensitive Unlock (bits 1 to 0) 00 = required, 01 = not required Silicon Revision Number (bits 7 to 2) | Yes |
| 46h | 8Ch | 0002h | Erase Suspend 00 = not supported, 01 = Read only, 02 = Read and Write | 2 |
| 47h | 8Eh | 0001h | Block Protection 00 = not supported, x = number of blocks in per group | 1 |
| 48h | 90h | 0001h | Temporary Block Unprotect 00 = not supported, 01 = supported | Yes |
| 49h | 92h | 0004h | Block Protect /Unprotect 04 = M29W400B | 4 |
| 4Ah | 94h | 0000h | Simultaneous Operations, 00 = not supported | No |
| 4Bh | 96h | 0000h | Burst Mode, 00 = not supported, 01 = supported | No |
| 4Ch | 98h | 0000h | Page Mode, 00 = not supported, 01 = 4 page Word, 02 = 8 page Word | No |

Table 26. Security Code Area

| Address | | Data | Description |
|---------|----------|------|------------------------------|
| x16 | x8 | | |
| 61h | C3h, C2h | XXXX | 64 bit: unique device number |
| 62h | C5h, C4h | XXXX | |
| 63h | C7h, C6h | XXXX | |
| 64h | C9h, C8h | XXXX | |

APPENDIX C. BLOCK PROTECTION

Block protection can be used to prevent any operation from modifying the data stored in the Flash memory. Each Block can be protected individually. Once protected, Program and Erase operations on the block fail to change the data.

There are three techniques that can be used to control Block Protection, these are the Programmer technique, the In-System technique and Temporary Unprotection. Temporary Unprotection is controlled by the Reset/Block Temporary Unprotection pin, \overline{RP} ; this is described in the Signal Descriptions section.

Unlike the Command Interface of the Program/Erase Controller, the techniques for protecting and unprotecting blocks could change between different Flash memory suppliers.

Programmer Technique

The Programmer technique uses high (V_{ID}) voltage levels on some of the bus pins. These cannot be achieved using a standard microprocessor bus, therefore the technique is recommended only for use in Programming Equipment.

To protect a block follow the flowchart in Figure 17, Programmer Equipment Block Protect Flowchart. During the Block Protect algorithm, the A19-A12 Address Inputs indicate the address of the block to be protected. The block will be correctly protected only if A19-A12 remain valid and stable, and if Chip Enable is kept Low, V_{IL} , all along the Protect and Verify phases.

The Chip Unprotect algorithm is used to unprotect all the memory blocks at the same time. This algorithm can only be used if all of the blocks are protected first. To unprotect the chip follow Figure 18,

Programmer Equipment Chip Unprotect Flowchart. Table 27, Programmer Technique Bus Operations, gives a summary of each operation.

The timing on these flowcharts is critical. Care should be taken to ensure that, where a pause is specified, it is followed as closely as possible. Do not abort the procedure before reaching the end. Chip Unprotect can take several seconds and a user message should be provided to show that the operation is progressing.

In-System Technique

The In-System technique requires a high voltage level on the Reset/Blocks Temporary Unprotect pin, \overline{RP} . This can be achieved without violating the maximum ratings of the components on the microprocessor bus, therefore this technique is suitable for use after the Flash memory has been fitted to the system.

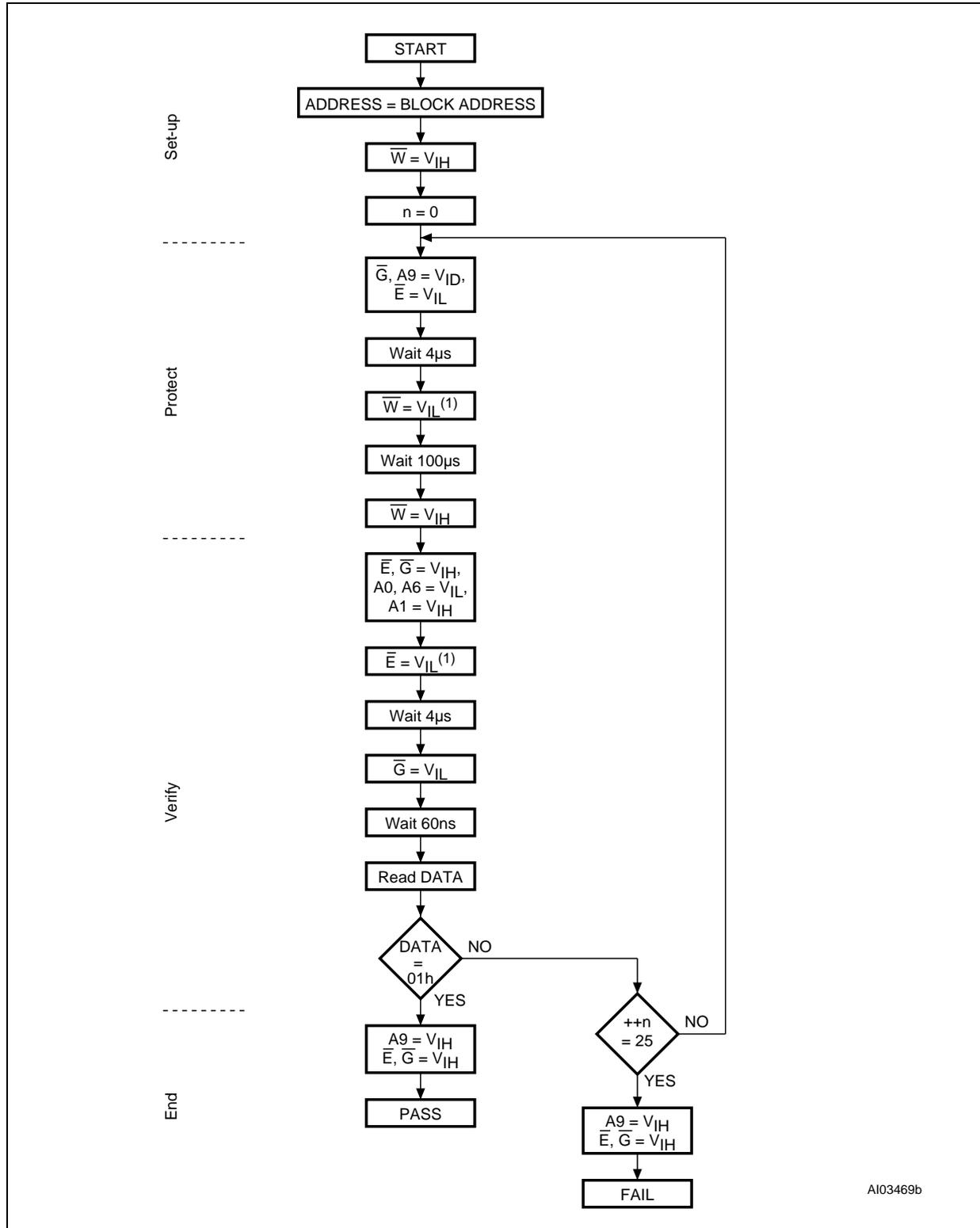
To protect a block follow the flowchart in Figure 19, In-System Block Protect Flowchart. To unprotect the whole chip it is necessary to protect all of the blocks first, then all the blocks can be unprotected at the same time. To unprotect the chip follow Figure 20, In-System Chip Unprotect Flowchart.

The timing on these flowcharts is critical. Care should be taken to ensure that, where a pause is specified, it is followed as closely as possible. Do not allow the microprocessor to service interrupts that will upset the timing and do not abort the procedure before reaching the end. Chip Unprotect can take several seconds and a user message should be provided to show that the operation is progressing.

Table 27. Programmer Technique Bus Operations, $\overline{BYTE} = V_{IH}$ or V_{IL}

| Operation | \overline{E} | \overline{G} | \overline{W} | Address Inputs A0-A19 | Data Inputs/Outputs DQ15A-1, DQ14-DQ0 |
|---------------------------|----------------|----------------|----------------|--|--|
| Block Protect | V_{IL} | V_{ID} | V_{IL} Pulse | A9 = V_{ID} , A12-A19 Block Address Others = X | X |
| Chip Unprotect | V_{ID} | V_{ID} | V_{IL} Pulse | A9 = V_{ID} , A12 = V_{IH} , A15 = V_{IH} Others = X | X |
| Block Protection Verify | V_{IL} | V_{IL} | V_{IH} | A0 = V_{IL} , A1 = V_{IH} , A6 = V_{IL} , A9 = V_{ID} , A12-A19 Block Address Others = X | Pass = XX01h Retry = XX00h |
| Block Unprotection Verify | V_{IL} | V_{IL} | V_{IH} | A0 = V_{IL} , A1 = V_{IH} , A6 = V_{IH} , A9 = V_{ID} , A12-A19 Block Address Others = X | Retry = XX01h Pass = XX00h |

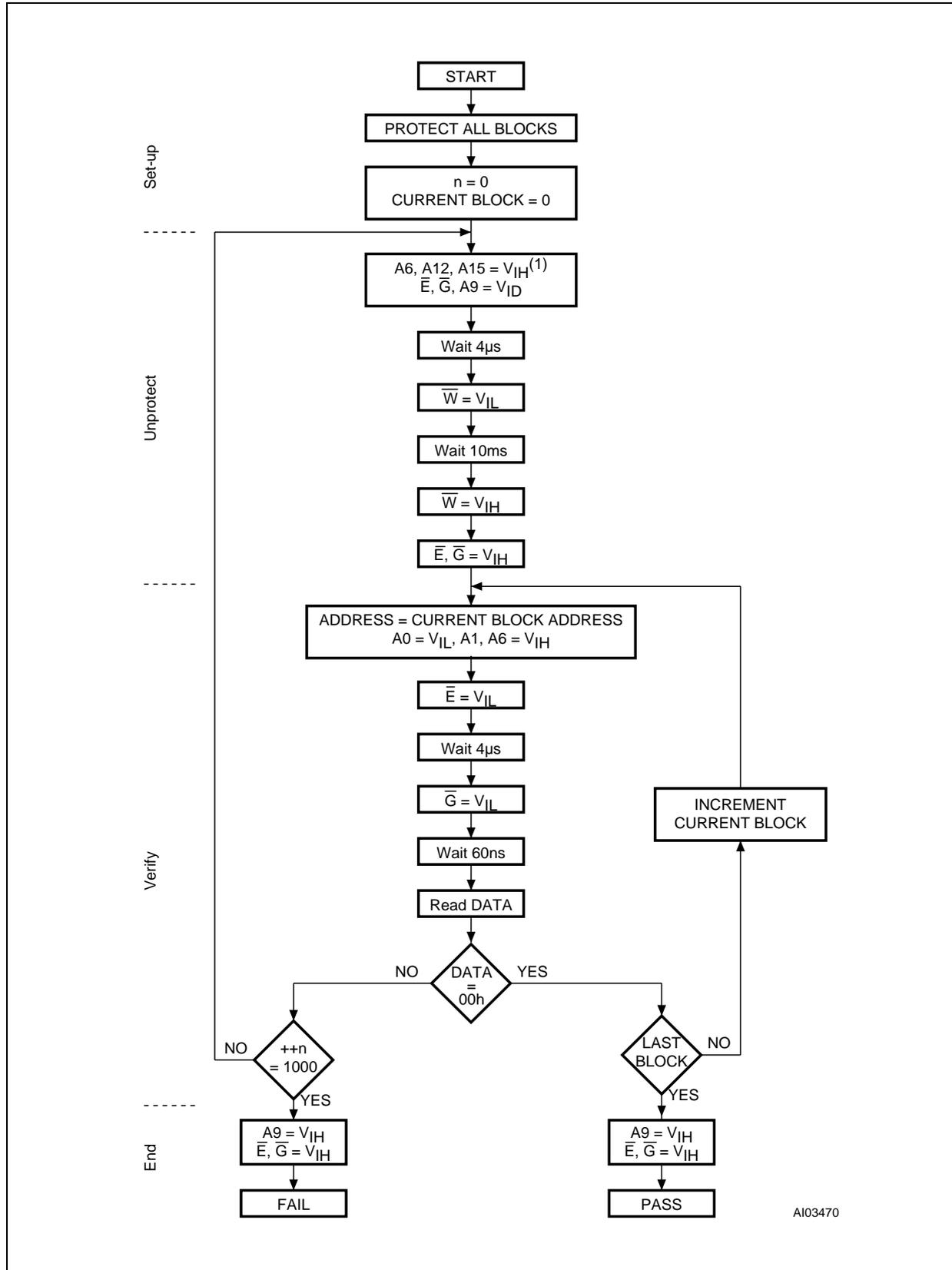
Figure 17. Programmer Equipment Block Protect Flowchart



Note: 1. Address Inputs A19-A12 give the address of the block that is to be protected. It is imperative that they remain stable during the operation.

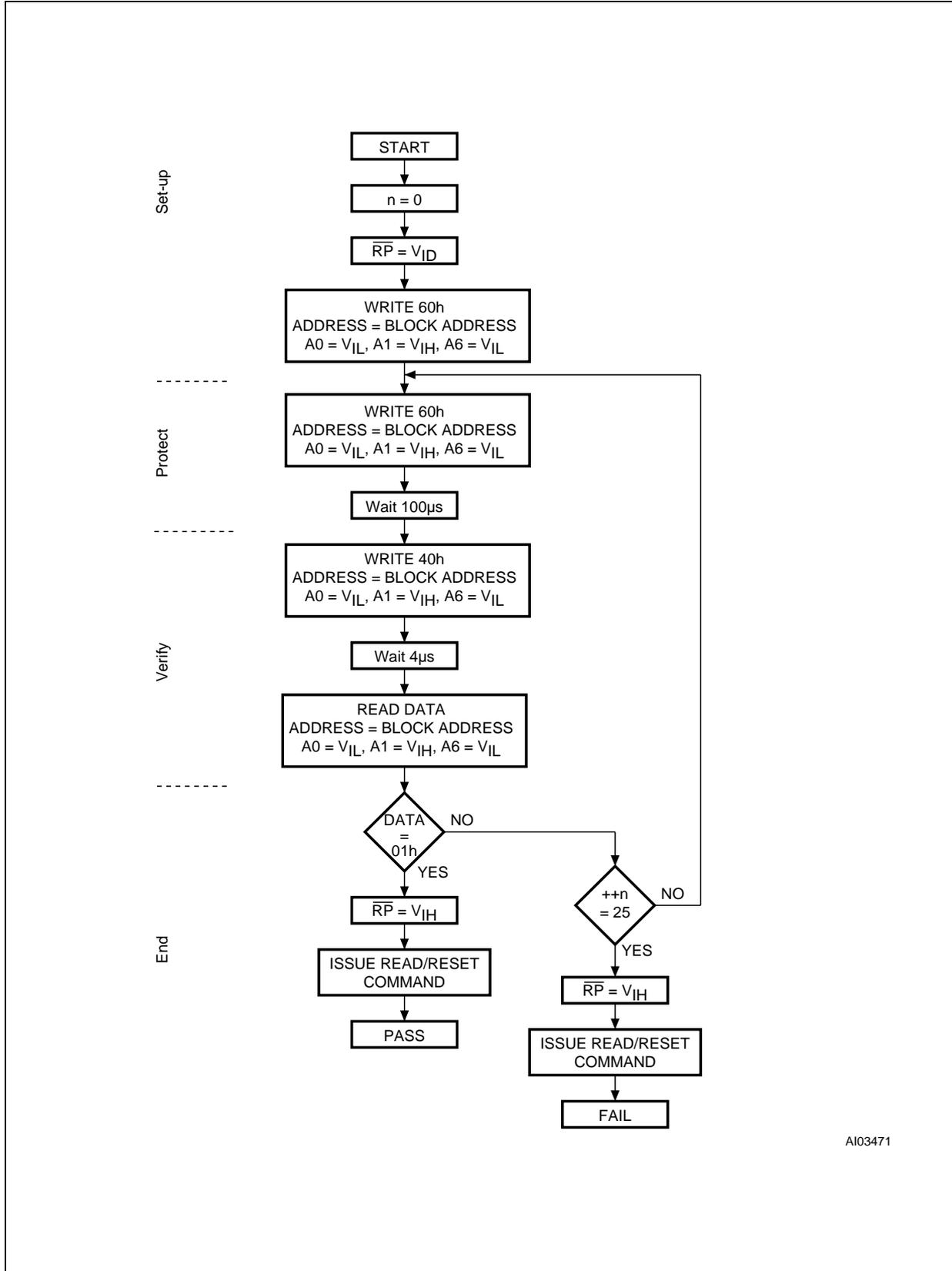
2. During the Protect and Verify phases of the algorithm, Chip Enable \overline{E} must be kept Low, V_{IL} .

Figure 18. Programmer Equipment Chip Unprotect Flowchart



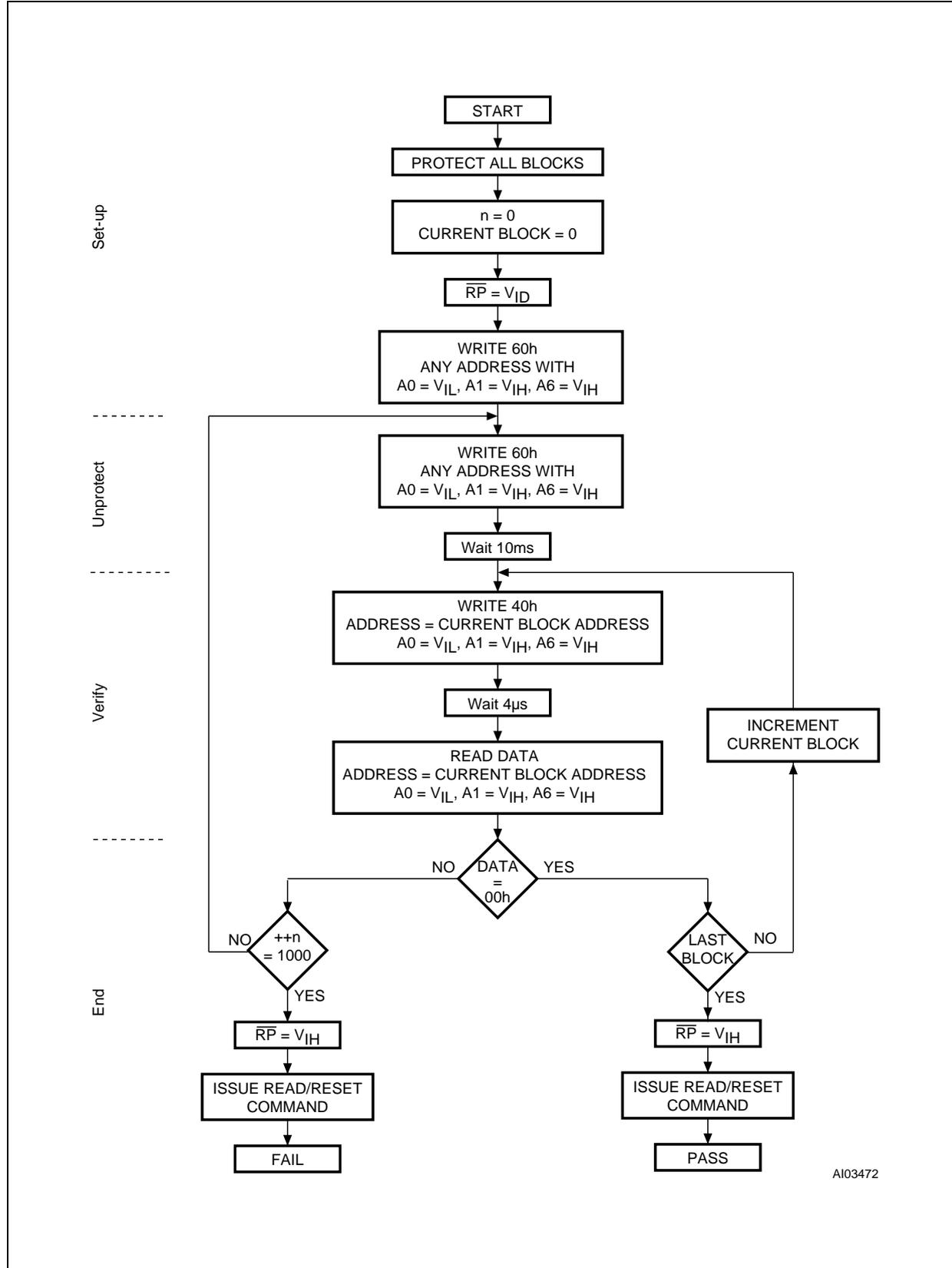
AI03470

Figure 19. In-System Equipment Block Protect Flowchart



AI03471

Figure 20. In-System Equipment Chip Unprotect Flowchart



AI03472

REVISION HISTORY**Table 28. Document Revision History**

| Date | Version | Revision Details |
|-------------|----------------|--|
| 06-Aug-2002 | -01 | First Issue: originates from M29W160D datasheet dated 24-Jun-2002 |
| 27-Nov-2002 | 1.1 | 9x8mm FBGA48 package replaced by 6x8mm. VDD(min) reduced for -70ns speed class. Erase Suspend Latency Time (typical and maximum) added to Program, Erase Times and Program, Erase Endurance Cycles table. Logic Diagram corrected. |
| 03-Dec-2002 | 1.2 | Package information corrected in ordering information table. |
| 21-Mar-2003 | 2.0 | Document promoted to full Datasheet status. Block Protect and Chip Unprotect algorithms specified in Appendix C, BLOCK PROTECTION. |
| 27-Jun-2003 | 2.1 | TSOP48 package information updated (see Figure 15 and Table 16). |

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